

TEM image simulation

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Introduction

The formation of Transmission Electron Microscopy (TEM) images involves complex physical processes that are characterized and modeled in order to perform computer simulations. There is no unique set of approximations that allows to model and calculate the numerous sorts of images that a TEM provides (in a more or less reasonable cpu time).

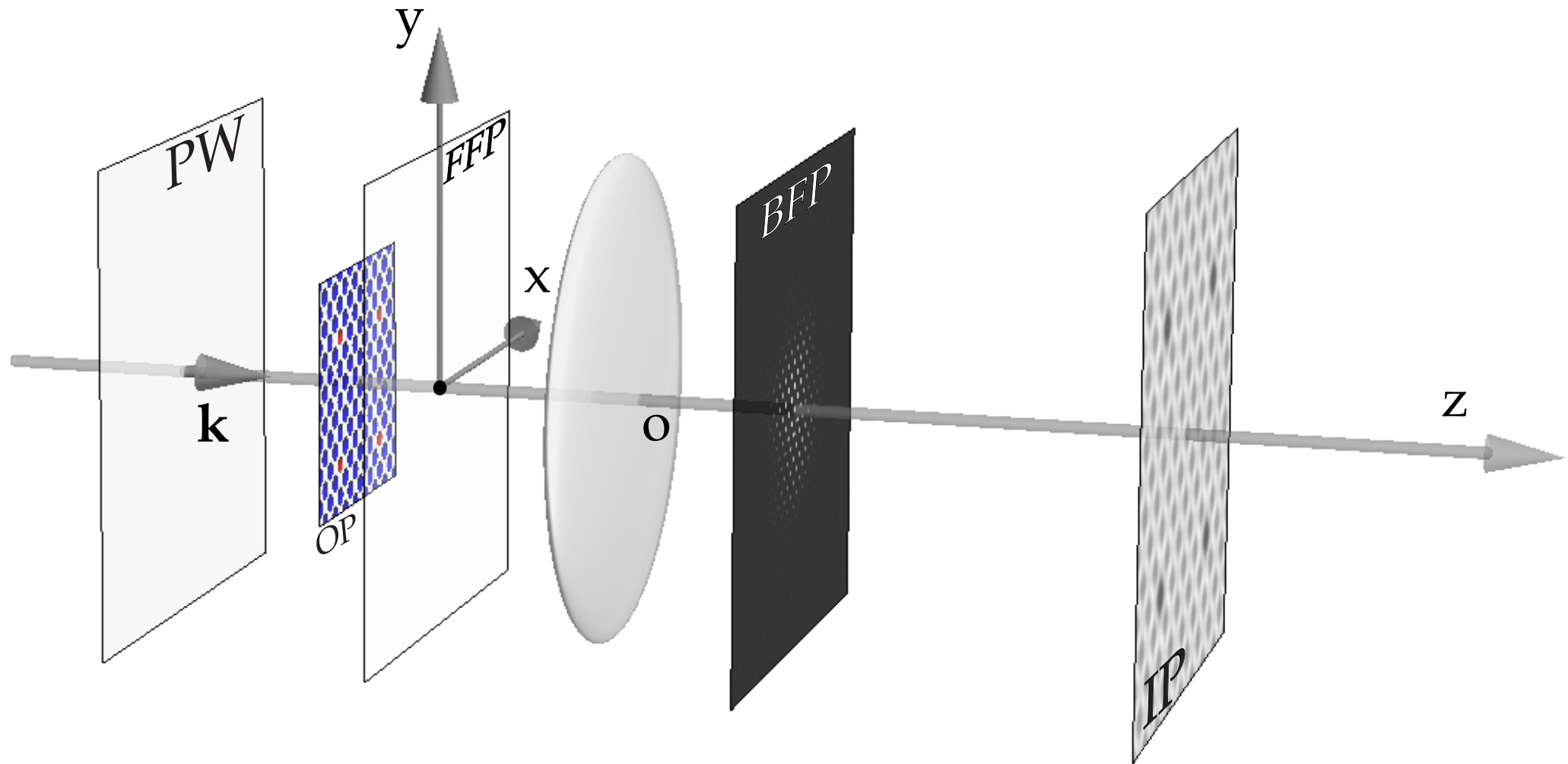
The approximations, assumed by the modeling process are strongly, dependent on the images to be simulated (SAED, CBED, LACBED or PED diffraction, HRTEM, Weak Beam, Hologram, ...). In this document we will describe some of them relevant to the simulation of diffraction patterns and high resolution TEM images.

Prior to perform any calculation the following items (from the electron source to the detector) must be characterized and modeled:

- ▶ The electron beam properties.
- ▶ The specimen properties¹.
- ▶ How are the incident electrons scattered by the specimen?
- ▶ How does the microscope transfer the scattered electron beam?
- ▶ How do we measure the properties of the scattered electron beam (diffraction, image, hologram)?

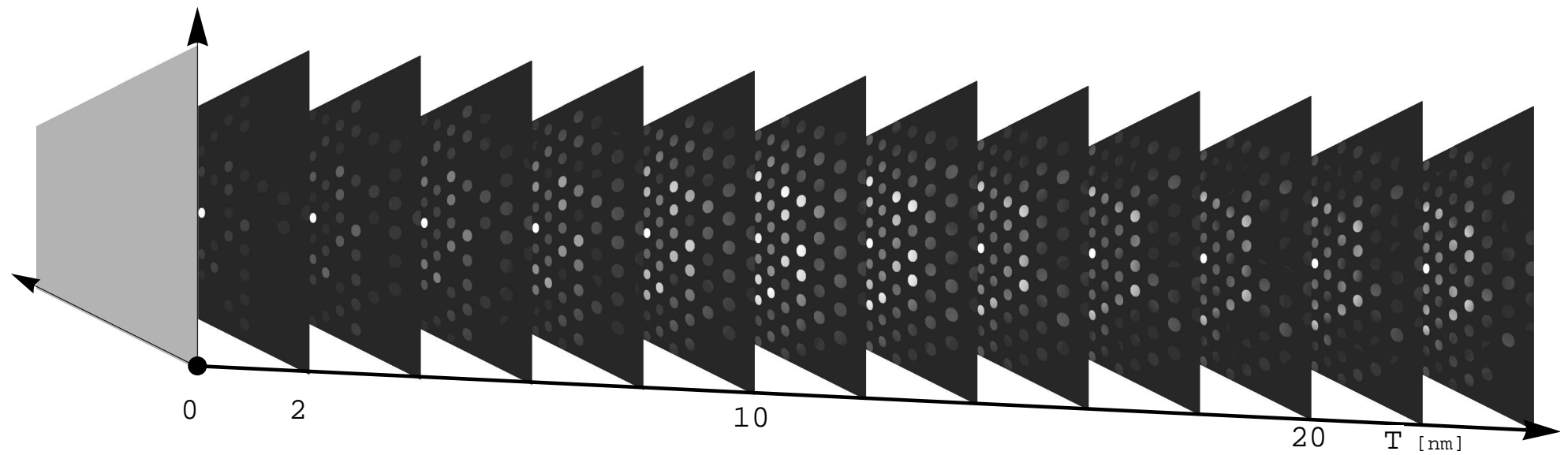
¹<file:///localhost/Users/pierrestadelmann/Desktop/HamiltonJune2012/html/Rb2W09/Rb2W09.html>

Modeling of TEM operation



Modeling steps: Incident wave, crystal, electron-matter interaction, Fraunhofer approximation, image formation.

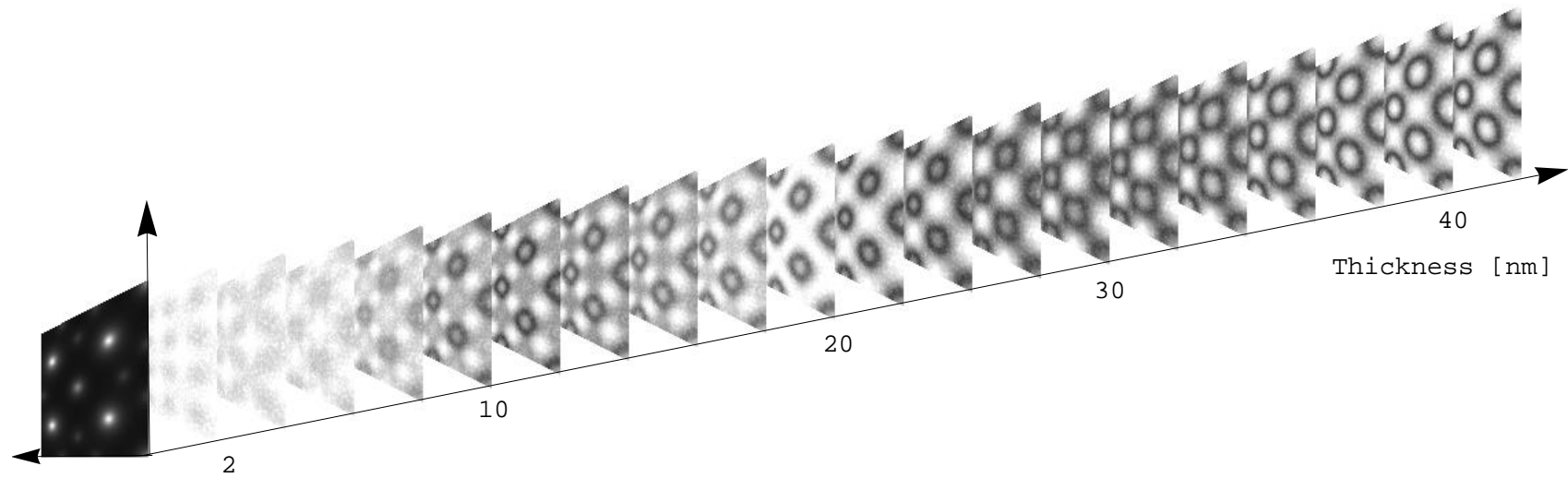
Diffraction pattern depends on specimen thickness



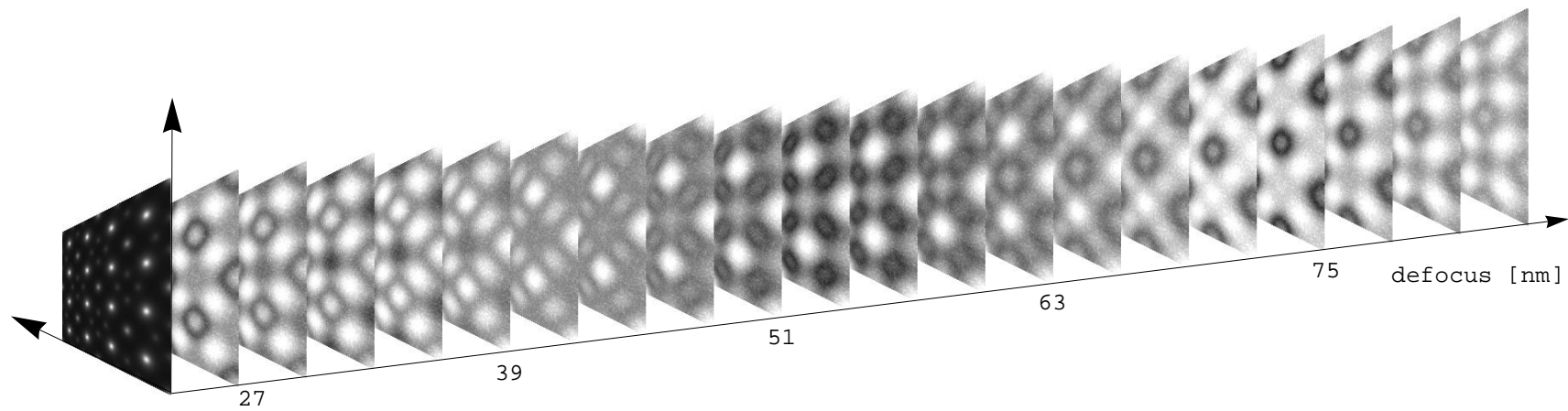
Dynamical diffraction

HRTEM image depends on specimen thickness and object defocus

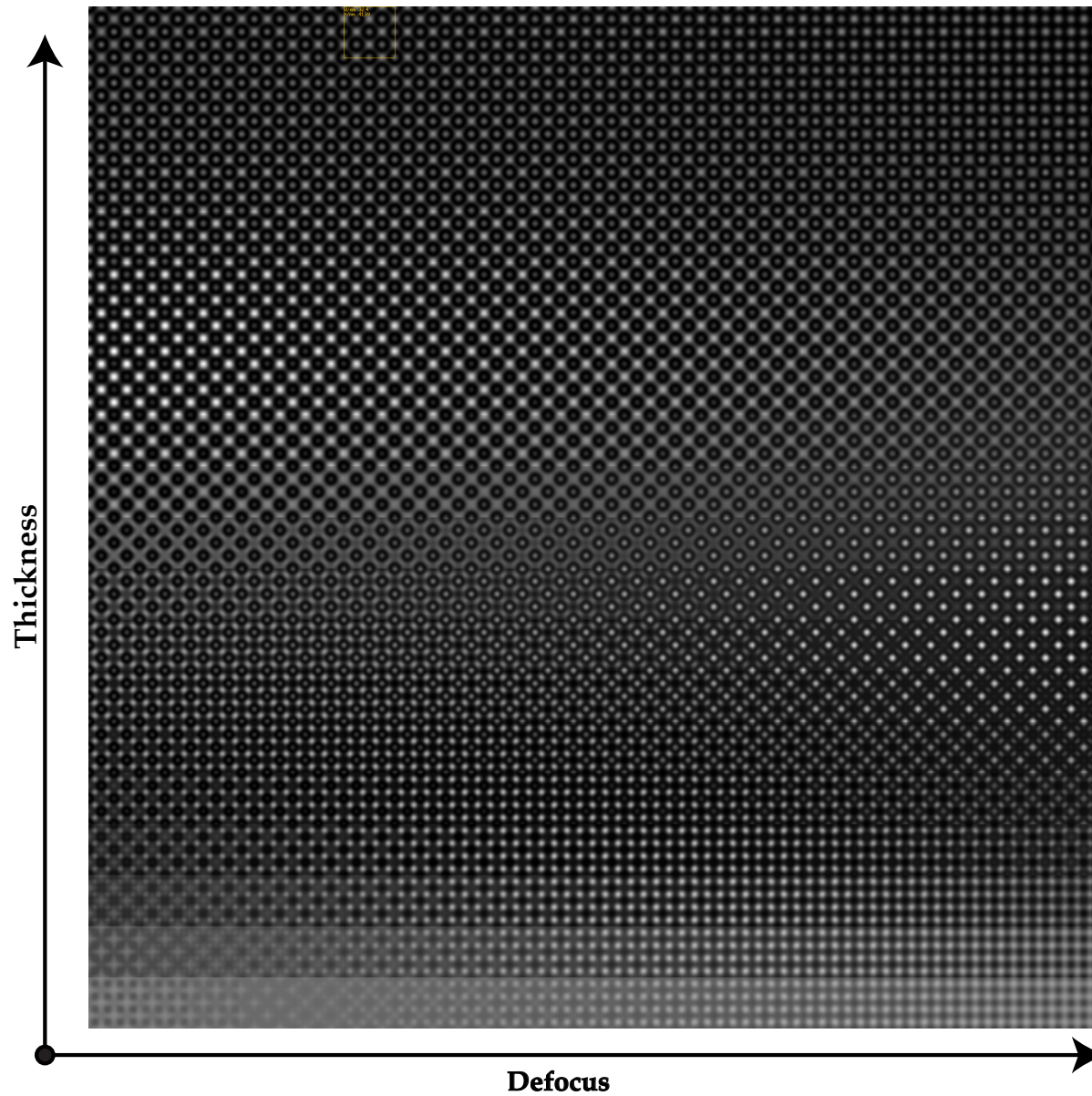
Thickness series



Defocus series



HREM map to show defocus - thickness dependence



HREM map does not include the Modulation Transfer Function (MTF) of the detector².

²See discussion of detector MTF below page 52.

The first modeling decision concerns the representation of a plane wave:

- ▶ Crystallography and optics: $\Psi(\vec{r}) = e^{2i\pi\vec{k}\cdot\vec{r}}$.
- ▶ Quantum mechanics: $\Psi(\vec{r}) = e^{i\vec{k}\cdot\vec{r}}$.

This choice has consequences for all the future modeling steps, in particular the description of the transfer function of the microscope and the controversial sign of the objective lens defocus³.

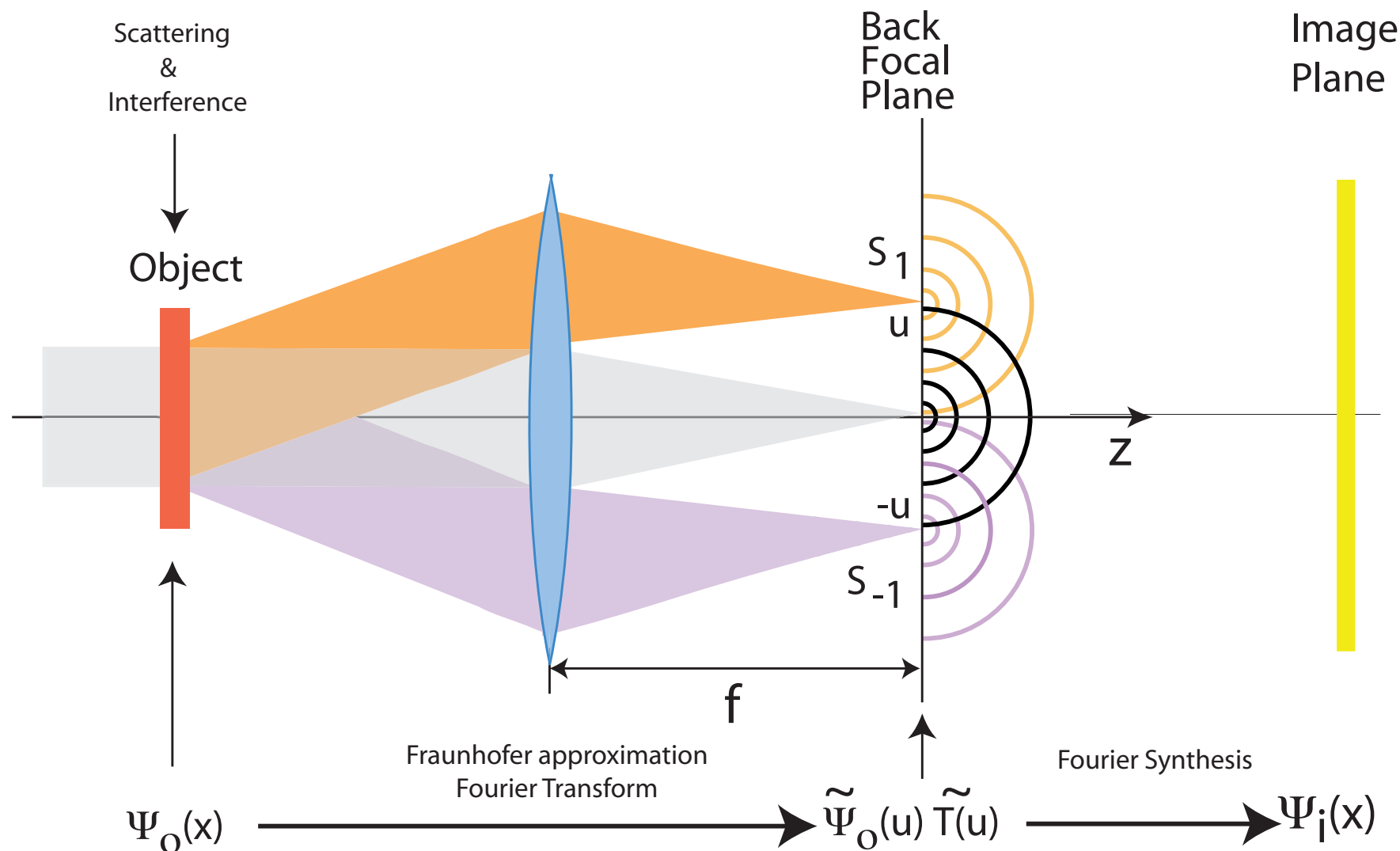
This choice determines also the choice of the phase shift of the transfer function of the objective lens and of the **underfocus** parameter⁴.

³L. Reimer, "*Transmission Electron Microscopy*", Springer-Verlag 1993.

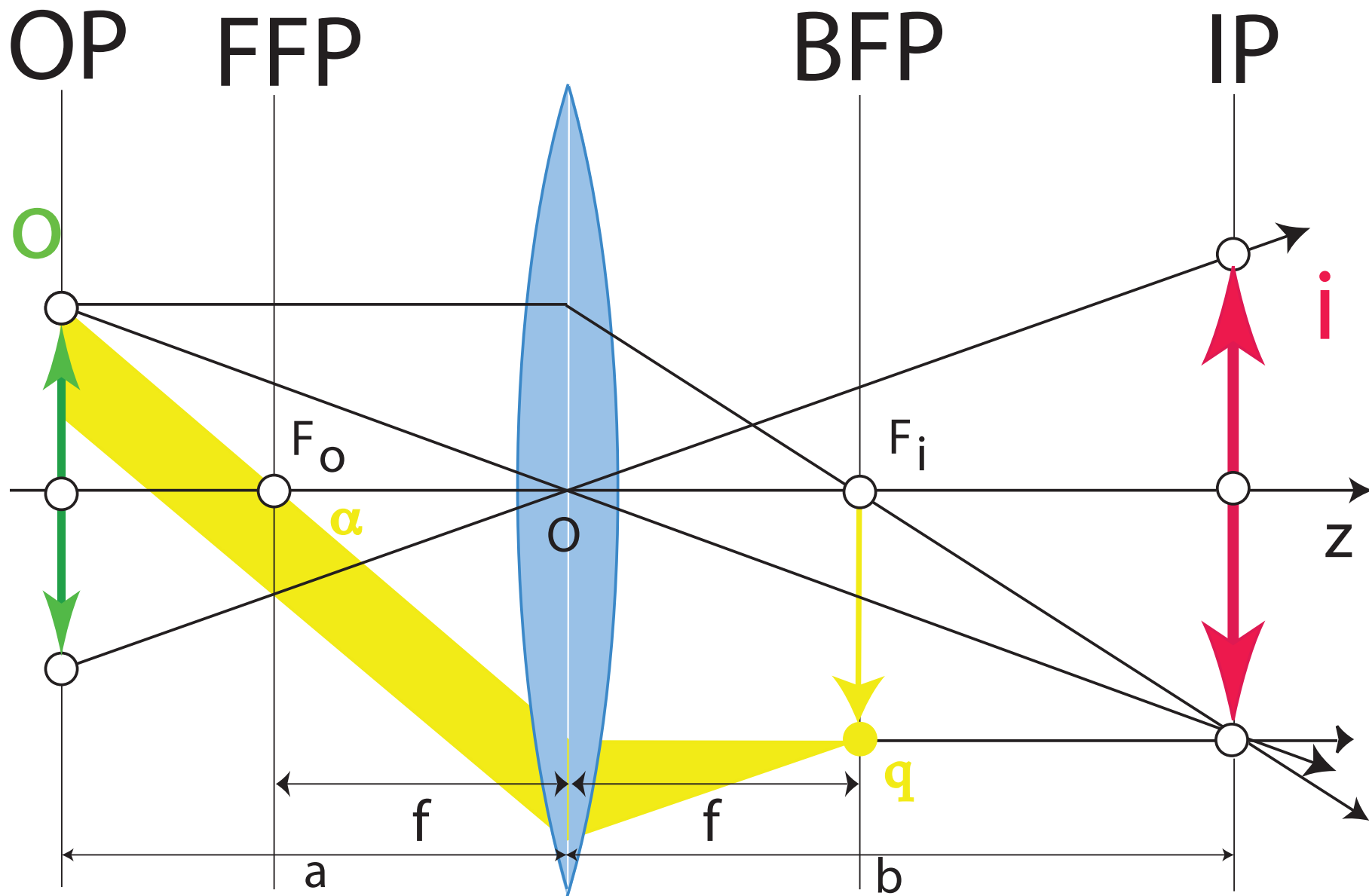
⁴See discussion on page 9.

Microscope modeling: Abbe image formation theory

The objective lens is modeled as a thin lens that brings the Fraunhofer diffraction pattern at a finite distance (i.e. in its back focal plane).

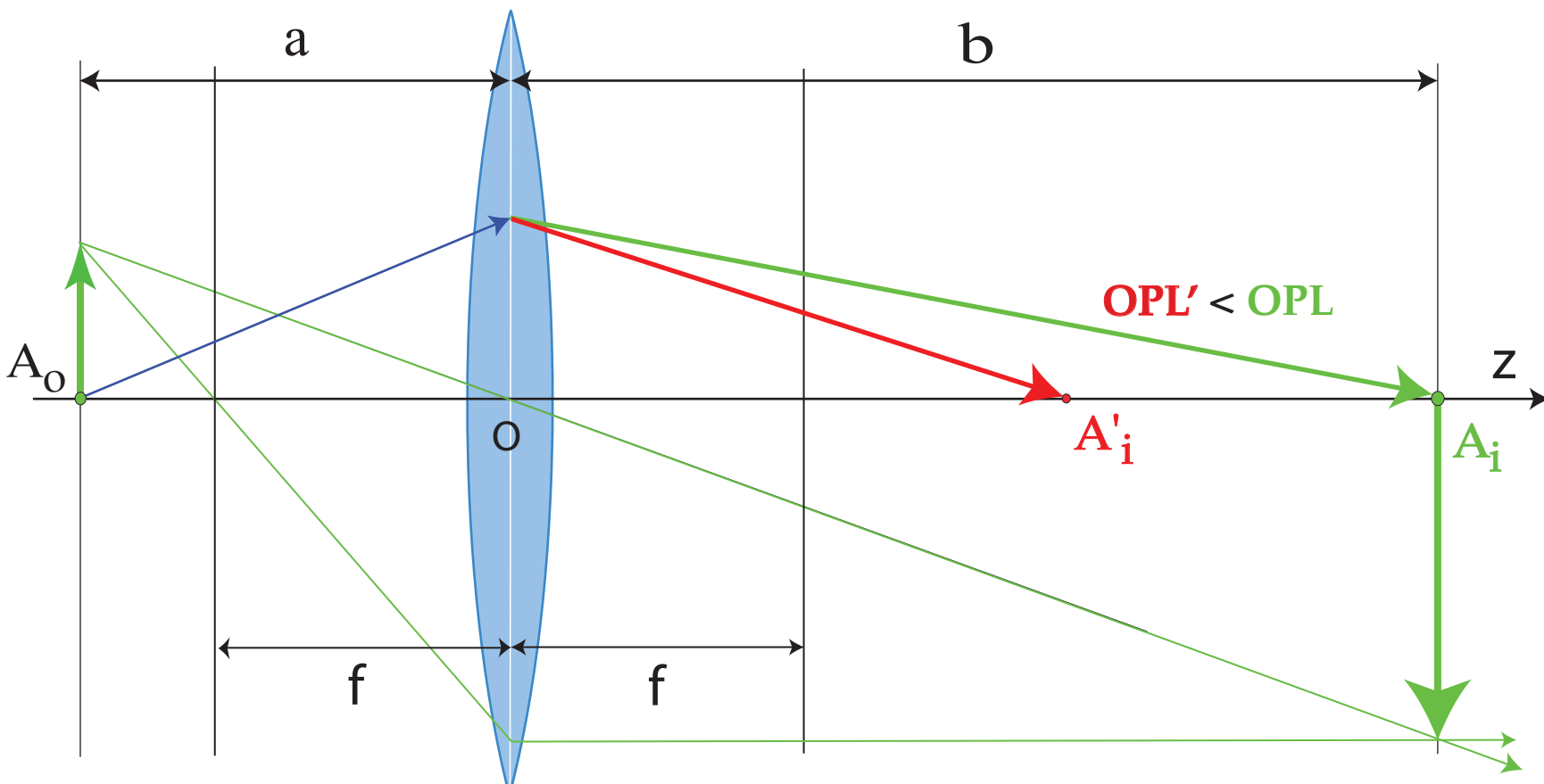


Paraxial optics: perfect thin lens



Principal rays of paraxial optics. Reflection (plane wave) making an angle α , where $\alpha = 2\theta_B$, corresponds to spatial frequency q .

Optical Path Length: spherical aberration

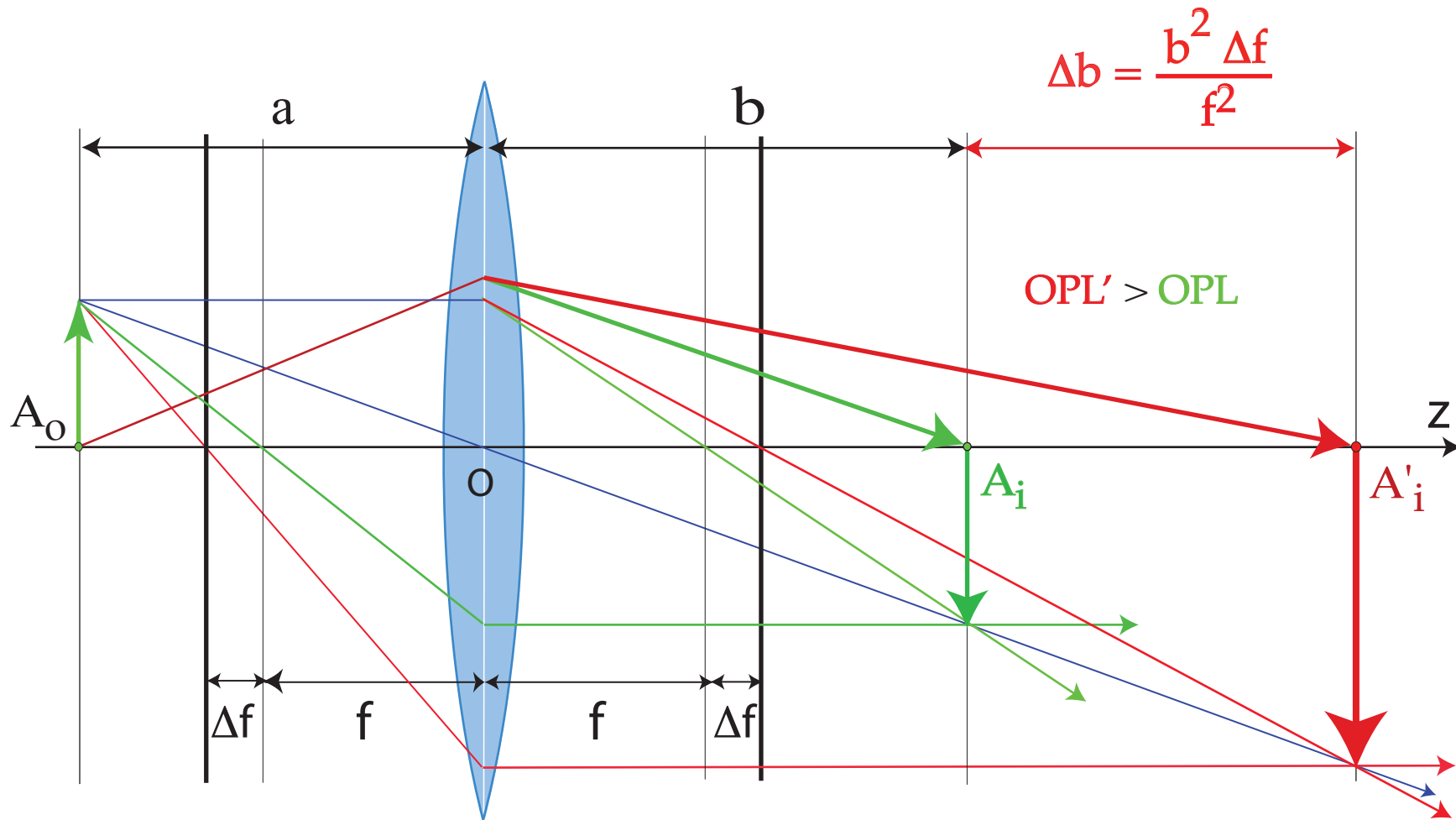


In presence of spherical aberration, the optical path length (OPL') from A_o to A'_i is smaller than OPL from A_o to A_i . The wavefront at A'_i is out-of-phase by⁵:

$$e^{-2\pi i \frac{C_s \lambda^3 (\vec{q} \cdot \vec{q})^2}{4}}$$

⁵With our plane wave choice.

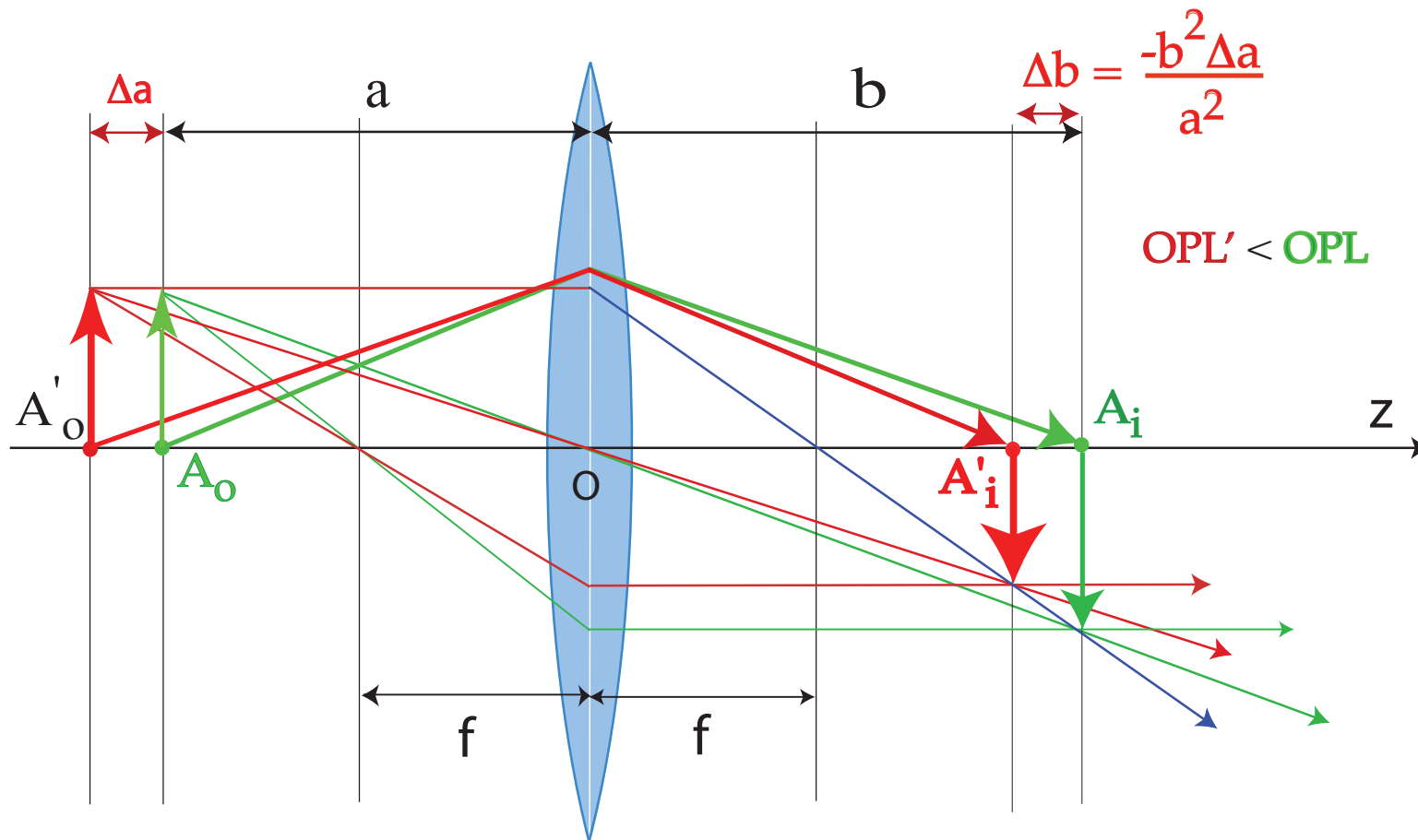
Optical Path Length: underfocus



Underfocus weakens the objective lens, i.e. increases f . As a consequence the OPL from A_0 to A'_i is larger:

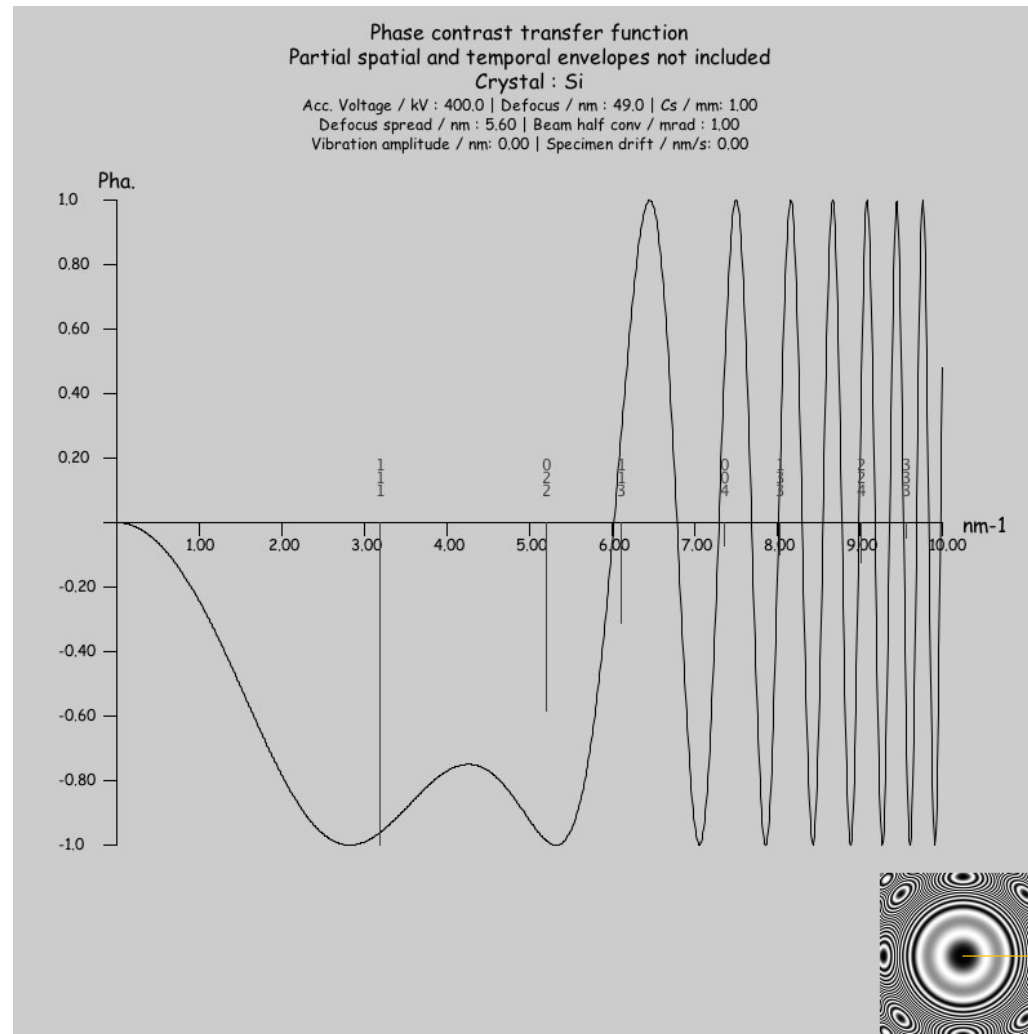
$$e^{2\pi i \frac{\Delta f \lambda (\vec{q} \cdot \vec{q})}{2}}$$

Optical Path Length: eucentricity



On the contrary keeping f constant and moving the object by Δa decreases the OPL.

Transfer function of the objective lens



The transfer function of the objective lens in the absence of lens current and accelerating voltage fluctuations (Scherzer defocus). The (111) and (022) reflections of Si are phase shifted by $-\frac{\pi}{2} \rightarrow$ black atomic columns.

1. Energy (E).
2. Energy dispersion or spread (ΔE).
3. Momentum dispersion or angular spread (ΔK).

These properties allow to describe the spatial and temporal coherence of the incident electron wave which are extremely important in high resolution imaging⁶.

⁶K. Ishizuka, "Contrast Transfer of Crystal Images in TEM", Ultramicroscopy 5 (1980) 55.

c = speed of light in vacuum.

e = electron charge.

E = accelerating voltage ($\geq 50kV$).

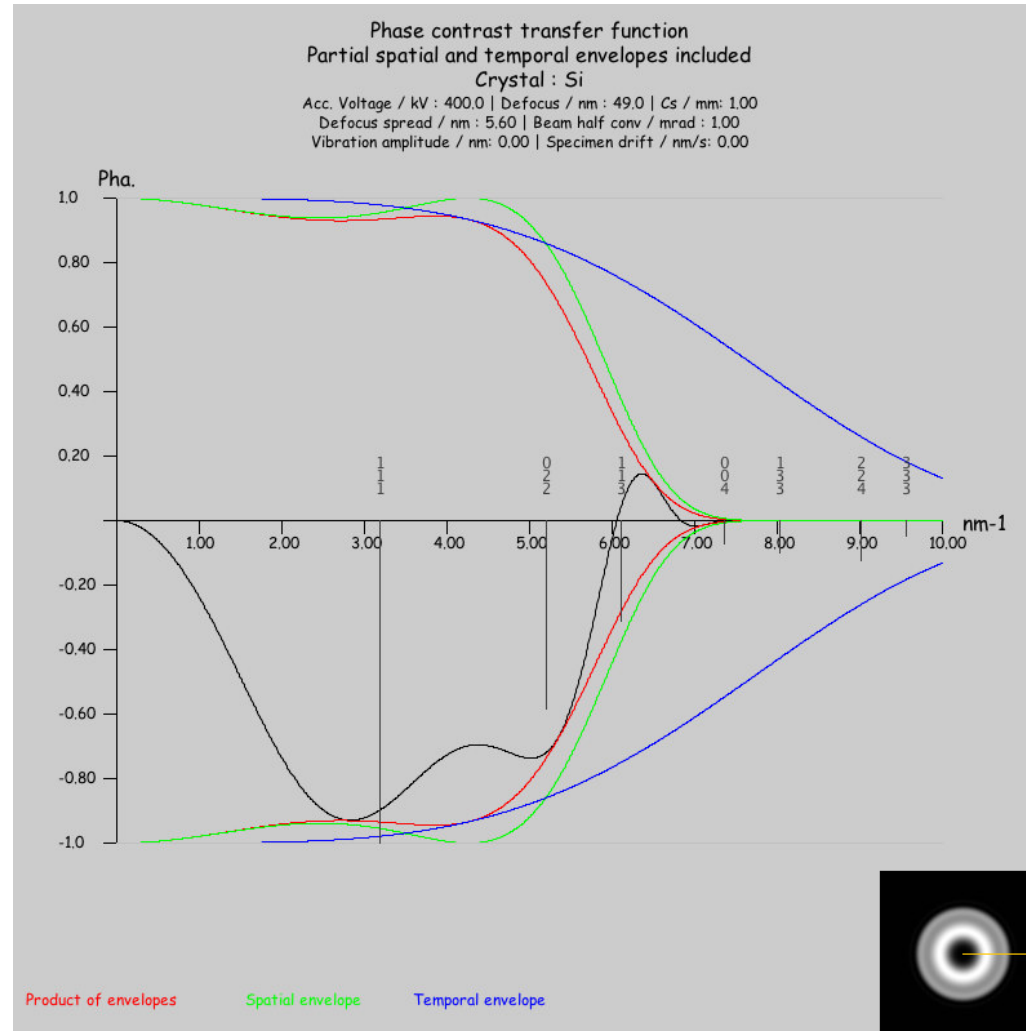
γ = $1 + \frac{e^2 E^2}{2 m_0 c^2}$ (relativistic mass correction).

m_0 = rest mass of the electron ($\approx 511 keV$).

$E [kV]$	γ	$\lambda [pm]$	$\frac{v}{c}$
50	1.098	5.362	0.412
100	1.119	3.706	0.548
200	1.391	2.511	0.695
500	1.978	1.423	0.862
1000	2.957	0.873	0.941

Relativistic mass correction, wavelength and speed of the electron.

Coherence of the electron beam

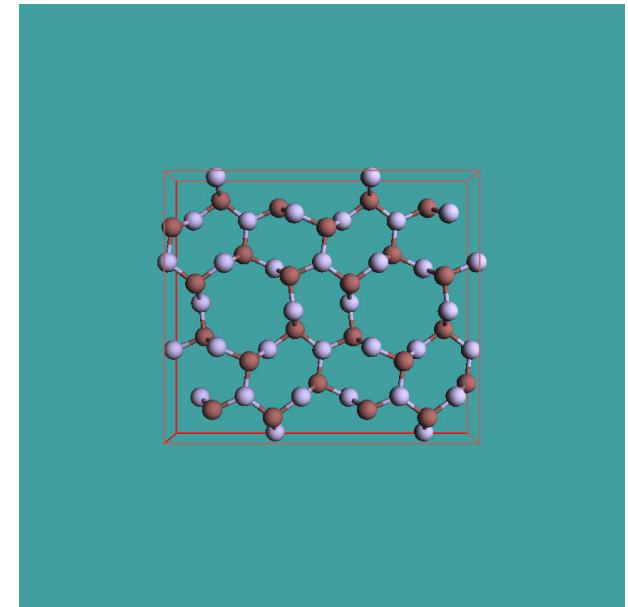
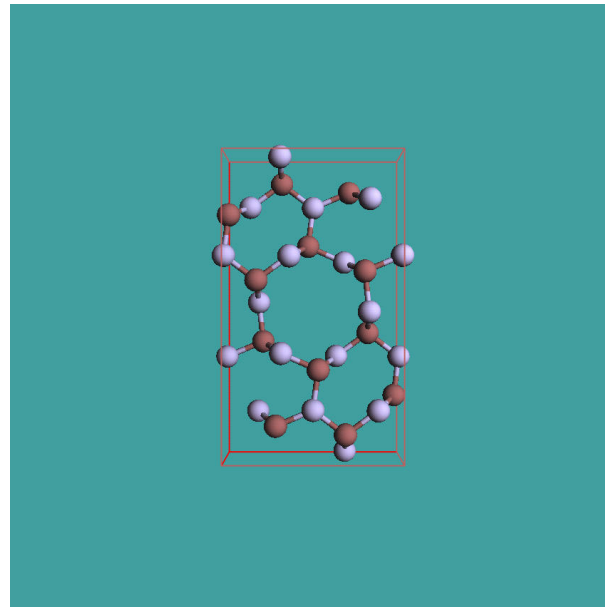
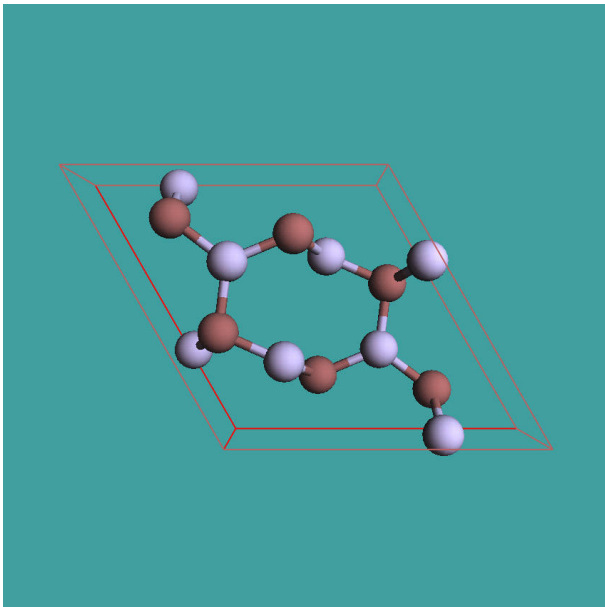


Partial spatial and temporal coherence of the electron beam introduce an attenuation of the transfer of high spatial frequencies.

Specimen properties

1. Amorphous material or crystalline material.
2. Thin or thick.
3. Orientation (high or low symmetry [uvw]).

You might have to transform the unit cell in order to perform the dynamical calculations⁷.



A: Si₃N₄ hexagonal lattice. B: Si₃N₄ orthorhombic lattice. C: Si₃N₄ orthorhombic lattice x 2.

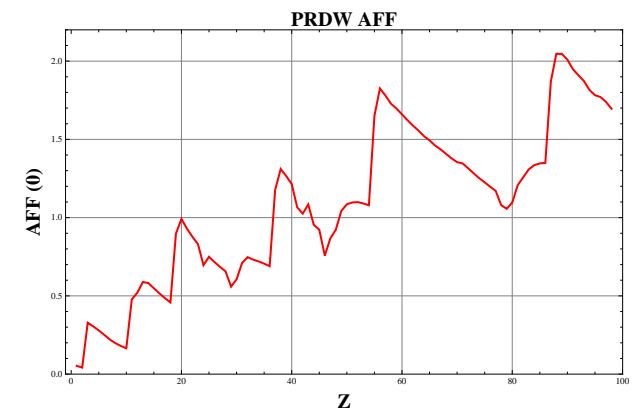
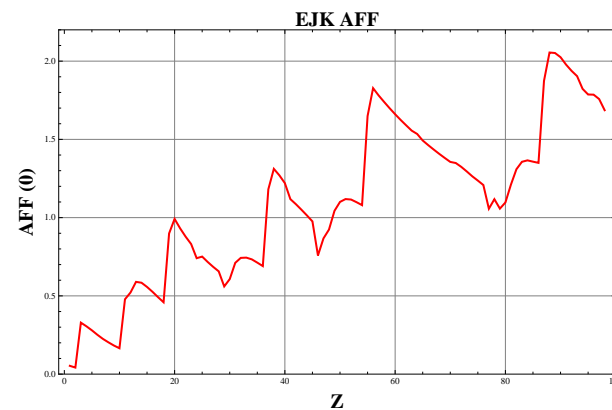
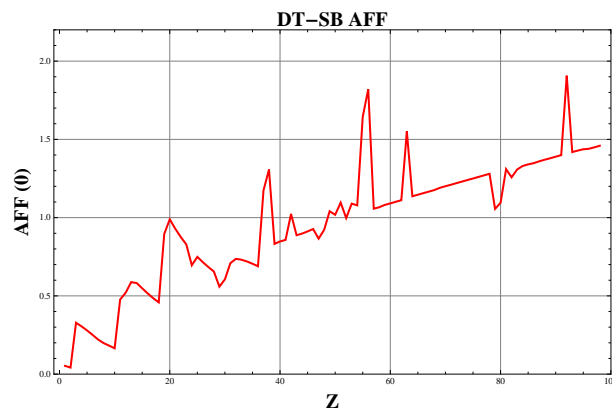
⁷See International Tables for Crystallography (1992) Vol. 1, Chapter 5.

Atomic form factors

Atomic form factors have been tabulated by many authors:

1. Doyle-Turner and Smith-Burge.
2. E.J. Kirkland.
3. Peng-Ren-Dudarev-Whelan.
4. ...

Take care ASA of heavy atoms aren't always tabulated properly.



A extremely useful ASA tabulation including phonon and core loss absorption is due to Weickenmeier-Kohl⁸.

⁸A. Weickenmeier, H. Kohl, Acta Cryst. A 47 (1991) 590.

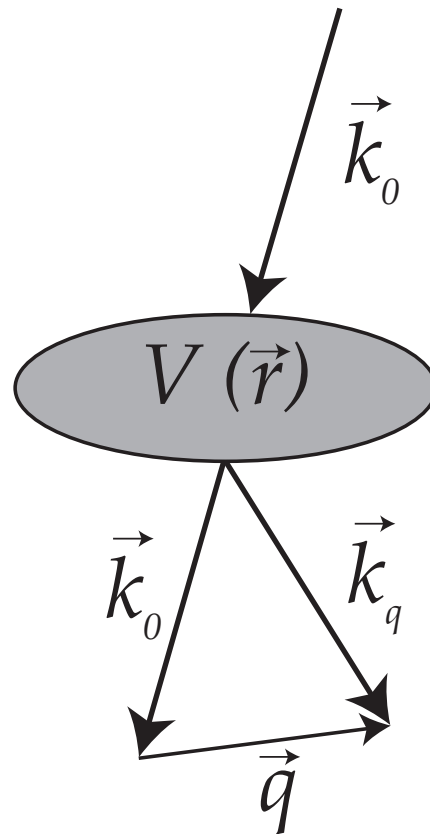
Typical Bragg angles

At 100 kV, Bragg angles for several reflections of Al are given in the next table.

(hkl)	Bragg angle [mrad]	Bragg angle [deg.]	(hkl) spacing nm^{-1}
(1,1,1)	7.91	0.453	4.276
(2,0,0)	9.14	0.523	4.938
(2,2,0)	12.92	0.740	6.983
(1,1,3)	15.15	0.868	8.189
(2,2,2)	15.83	0.906	8.553
(4,0,0)	18.28	1.047	9.876

Bragg angles for some Al reflections at 100 kV.

Notice that the Bragg angles are **pretty small** (of the order a few $^\circ$) and that consequently the **small angle approximation** is quite good.



An incident electron of wave vector \vec{k}_0 interacts with a solid of scalar potential $V(\vec{r})$. The wave vector of the scattered electron is $\vec{k}_q = \vec{k}_0 + \vec{q}$ where \vec{q} is the momentum transferred by the solid⁹.

⁹Magnetic and spin effects are ignored.

Approximations: elastic scattering of high energy electrons

Elastic scattering:

- ▶ Energy conservation ($\Delta E = 0$).
- ▶ Momentum transfer ($q \geq 0$).
- ▶ Scattering of high energy electrons (i.e. electrons accelerated by potential ≥ 50 kV):
 - ▶ \implies electrons scattered at small angles (few degrees).
- ▶ Strong electron-matter interaction (10^4 times larger X-rays):
 - ▶ \implies very thin crystals only can be imaged.
 - ▶ \implies Relaxed Bragg condition (reciprocal rod - many reflections).

\vec{k}_i : incident wavevector

\vec{k}_g : scattered wavevector

\vec{g} : reciprocal lattice vector

\vec{s}_g : deviation from exact Bragg condition

1. Energy conservation: $|\vec{k}_g| = |\vec{k}_i|$.

2. Momentum transfer: $\vec{k}_i + \vec{g} + \vec{s}_g = \vec{k}_g$.

With energy conservation and momentum transfer ($\vec{s}_g = 0$):

$$|\vec{k}_i + \vec{g}| = |\vec{k}_g|$$

$$k_i^2 + 2 \times k_i \times g \times \cos(\vec{k}_i, \vec{g}) + g^2 = k_g^2$$

$$2k_i \times \cos(\vec{k}_i, \vec{g}) = -g$$

$$2k_i \times \cos(90^\circ - \theta_B) = -g$$

$$\frac{2}{\lambda} \times \sin(\theta_B) = g = \frac{1}{d_g}$$

\implies Bragg law:

$$2 \times d_{hkl} \times \sin(\theta_B) = \lambda$$

Kinematically the intensity of any reflection (or diffracted spot as observed on a CCD camera) is proportional to I_{hkl} :

$$I_{hkl} = F_{hkl}^* F_{hkl}$$

where the structure factor F_{hkl} is:

$$F_{hkl} = \sum_{i=atoms} f_i(hkl) \exp^{-[2i\pi(hx_i+ky_i+lz_i)]} occ_i DW_i(hkl)$$

⇒ Single scattering approximation only valid for extremely thin crystals.

Fundamental equation

The fundamental equation of the scattering of an electron by a scalar potential $V(\vec{r})$:

$$(\hat{\Delta} + k_0^2)|\Phi\rangle = V(\vec{r})|\Phi\rangle$$

The Dirac notation is used in this document¹⁰. Observing that the incident electrons have a kinetic energy several orders of magnitude larger than the interaction energy, one can write (see figure page 19):

$$|\Phi\rangle = e^{ik_z z}|\Psi\rangle = e^{ik_z z} e^{i\pi\vec{\chi}\cdot\vec{\rho}}$$

The electron propagation is thus decomposed into 2 parts:

- ▶ A very fast movement along the z direction where the electron has an energy several orders of magnitude larger than the interaction potential.
- ▶ A movement in the (x, y) plane where the kinetic and potential energies are of comparable.

The following equation is obtained¹¹ under the elastic and small angle scattering approximations:

$$i\frac{d}{dz}|\Psi(z)\rangle = \hat{H}(z)|\Psi(z)\rangle$$

It is similar to the time dependent Schrödinger equation where time t is replaced by z.

¹⁰The notation is provided on page 26.

¹¹See development page 58.

Notation

- ▶ Vector in 3-D: $\vec{r} = \{\vec{\rho}, z\} = (x, y, z)$
- ▶ Vector in 2-D: $\vec{\rho} = (x, y)$
- ▶ Wave vector 3-D: $\vec{k} = \{\vec{\chi}, k_z\}$
- ▶ Momentum 2-D: \vec{q}
- ▶ Closure: $\sum |\vec{q}\rangle \langle \vec{q}| = 1$
- ▶ Reciprocal lattice vector: \vec{g} or \vec{h}
- ▶ Closure reciprocal basis: $\sum |\vec{g}\rangle \langle \vec{g}| = 1$ or $\sum |\vec{h}\rangle \langle \vec{h}| = 1$
- ▶ Operator: $\hat{O} = \sum o_j |j\rangle \langle j|$ where the o_j and $|j\rangle$ are the eigenvalues¹² and eigenfunctions of \hat{O} .
- ▶ Projector on state $|j\rangle$: $|j\rangle \langle j|$
- ▶ Plane wave of wave vector \vec{k} (3-D): $\psi(\vec{r}) = e^{i\vec{k} \cdot \vec{r}}$
- ▶ Plane wave of wave vector \vec{q} (2-D): $\phi(\vec{\rho}) = e^{i\vec{q} \cdot \vec{\rho}}$
- ▶ Transfer function¹³ $T(\vec{q}, \Delta z)$: $T(\vec{q}, \Delta z) = e^{-i2\pi \left[\frac{C_s \lambda^3 (\vec{q} \cdot \vec{q})^2}{4} - \frac{\Delta z \lambda \vec{q} \cdot \vec{q}}{2} \right]}$

¹²Eigenvalues are real when operator is hermitic.

¹³Note that the defocus Δz is positive for underfocus.

Initial state and signs

Initial state $|\chi\rangle$:

$$|\chi\rangle = e^{i\pi\vec{\chi}\cdot\vec{\rho}}$$

Fourier transform (3-D):

$$\langle \vec{u} | \vec{k} \rangle = \int_{-\infty}^{\infty} e^{-i\vec{u}\cdot\vec{r}} \psi(\vec{r}) d\vec{r} = \int_{-\infty}^{\infty} e^{-i\vec{u}\cdot\vec{r}} e^{i\vec{k}\cdot\vec{r}} d\vec{r} = \delta(\vec{k} - \vec{u})$$

Fourier transform (2-D):

$$\langle \vec{q} | \vec{q}' \rangle = \int_{-\infty}^{\infty} e^{-i\vec{q}\cdot\vec{\rho}} \psi(\vec{\rho}) d\vec{\rho} = \int_{-\infty}^{\infty} e^{-i\vec{q}\cdot\vec{\rho}} e^{i\vec{q}'\cdot\vec{\rho}} d\vec{\rho} = \delta(\vec{q}' - \vec{q})$$

Structure factor $F_{\vec{h}}$ of a unit cell with N atoms at \vec{x}_i , Debye-Waller temperature factor $e^{-DWi\frac{\vec{h}\cdot\vec{h}}{4}}$ and site occupancy Oc^i :

$$F_{\vec{h}} = \sum_{i=1}^{i=N} f_{\vec{h}}^i e^{-i2\pi\vec{h}\cdot\vec{x}_i} e^{-DWi\frac{\vec{h}\cdot\vec{h}}{4}} Oc^i$$

Phase object function $O(\vec{\rho})$ with projected potential $V_p(\vec{\rho})$ (positive):

$$O(\vec{\rho}) = e^{i\sigma_e V_p(\vec{\rho})}$$

Weak phase object approximation $WPOA(\vec{\rho})$:

$$WPOA(\vec{\rho}) = 1 + i\sigma_e V_p(\vec{\rho})$$

Fresnel propagator $P(\vec{\rho}, z)$:

$$P(\vec{\rho}, z) = e^{ik_z \frac{\vec{\rho} \cdot \vec{\rho}}{2z}}$$

Evolution operator

It is a postulate of quantum mechanics that the temporal evolution of a system is given by:

$$\begin{aligned} |\Psi(t) \rangle &= \hat{U}(t, t_0) |\Psi(t_0) \rangle = \hat{U}(t, t_1) \hat{U}(t_1, t_0) |\Psi(t_0) \rangle \quad t \geq t_1 \geq t_0 \\ \hat{U}(t, t) &= \hat{1} \\ \hat{U}(t_0, t) &= \hat{U}^\dagger(t, t_0) \end{aligned}$$

In our case z replaces t and the evolution of the system from the initial state $|\Psi(0) \rangle$ at $z = 0$ to the final state $|\Psi(z) \rangle$ at z :

$$|\Psi(z) \rangle = \hat{U}(z, z_0) |\Psi(z_0) \rangle$$

The evolution operator is the solution of:

$$i \frac{d}{dz} \hat{U}(z, z_0) = \hat{H}(z) \hat{U}(z, z_0)$$

Where $\hat{H}(z)$ is the hamiltonian of elastic diffraction:

$$\hat{H}(z) = \frac{1}{2k_z} \left(\sum_q (q^2 - \chi^2) |q\rangle \langle q| + \sum_{q, q'} |q\rangle \langle q| V(z) |q'\rangle \langle q'| \right)$$

Hamiltonian of elastic diffraction

$\hat{H}(z)$ depends on the space variable (x, y) and z in the direction of propagation behaves like the time parameter of the Schrödinger equation.

The diagonal terms $(q^2 - \chi^2) \hat{H}(z)$ are the deviations s_q from exact Bragg condition. They are calculated as¹⁴:

$$q^2 - \chi^2 = |\vec{\chi} + \vec{g}|^2 - \chi^2 = \chi^2 + 2\vec{\chi} \cdot \vec{g} + g^2 - \chi^2 = 2\vec{\chi} \cdot \vec{g} + g^2$$

The off-diagonal terms $\langle q|V(z)|q' \rangle$ of $\hat{H}(z)$ are the 2-D Fourier coefficients of the scattering potential.

As the diagonal terms increases quadratically with $|q|$, whereas the off-diagonal terms decrease to zero for large values of $|q|$, reciprocal nodes Q far away from the Ewald sphere do not contribute to diffraction. One can restrict the q basis to vectors such that q^2 is not too large compared to the maximum value of $\langle q|V(z)|q' \rangle$.

¹⁴see figure page 19.

Final state $|\Psi_z\rangle$ of electron after interaction with potential $V(\vec{\rho}, z)$:

$$|\Psi_z\rangle = \hat{U}(z, 0)|\Psi_0\rangle$$

Transition probability from the **initial state** $|\chi\rangle$ to the final state $|q\rangle$, $\omega_{\chi \rightarrow q}(z, 0)$, is the module square of $\langle q|\hat{U}(z, 0)|\chi\rangle$ (intensity of beam diffracted to $|q\rangle$).

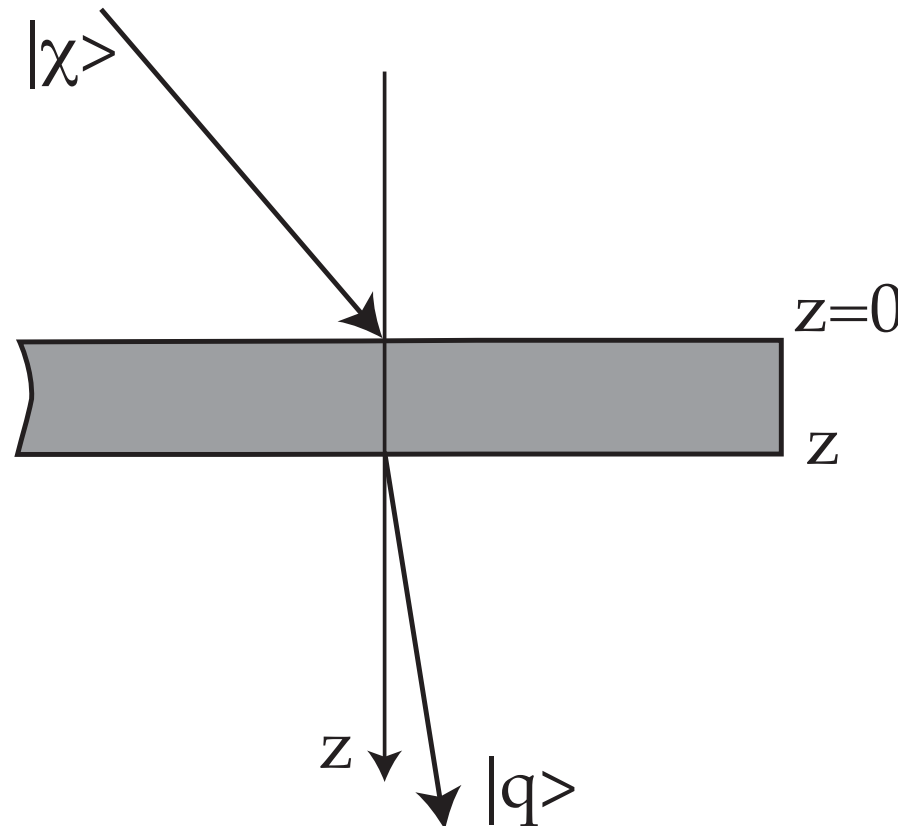
Intensity diffracted to $|q\rangle$:

$$\omega_{\chi \rightarrow q}(z, 0) = |\langle q|\hat{U}(z, 0)|\chi\rangle|^2$$

Intensity of diffracted beam $|q\rangle$

The transition probability from $|\Psi(z_0)\rangle$ or **initial state** $|\chi\rangle$ to **some final state** $|q\rangle$.

$$\omega_{\chi \rightarrow q}(z, 0) = |\langle q | \hat{U}(z, 0) | \chi \rangle|^2$$



To calculate the intensity or transition probability $\omega_{\chi \rightarrow q}(z, 0)$ we must calculate $\hat{U}(z, 0)$

Intensity of the wave function

Wave function intensity $\Psi(\rho; z)$ at exit face of crystal slab \implies transition probability from **initial state** $|\chi\rangle$ to **final state** $|\rho\rangle$:

$$\omega_{\rho \rightarrow \chi}(z, 0) = |\langle \rho | \hat{U}(z, 0) | \chi \rangle|^2$$

With a discrete set of $|q\rangle$:

$$\omega_{\rho \rightarrow \chi}(z, 0) = \left| \sum_q \langle \rho | q \rangle \langle q | \hat{U}(z, 0) | \chi \rangle \right|^2$$

Where:

- ▶ $\langle q | \hat{U}(z, 0) | \chi \rangle$ Fourier transform of object wave function.
- ▶ $\sum_q \langle \rho | q \rangle \langle q | \hat{U}(z, 0) | \chi \rangle$ the Fourier synthesis of the image wave function.

Intensity observed at point ρ in the image plane **is modified** by the transfer function of the microscope $T(q', q)$ that couples states $|q' \rangle$ and $|q \rangle$ (matrix $T(q', q)$).

Image intensity is given by:

$$\omega_o \rightarrow \rho(z, 0) = \left| \sum_q \sum_{q'} \langle \rho | q' \rangle \langle q' | T(q', q) | q \rangle \langle q | \hat{U}(z, 0) | \chi \rangle \right|^2$$

Fourier components of the wave function in image plane of objective lens are modified by $\langle q' | T(q', q) | q \rangle$ (Abbe theory of image formation).

Abbe image formation: transfer function

The terms $\sum_{q'} \langle \rho | q' \rangle$ show that the wave function is obtained by inverse Fourier transform (**Fourier synthesis**).

In back focal plane of objective lens Fourier components of image wave function:

$$\langle q' | T(q', q) | q \rangle \langle q | \hat{U}(z, 0) | \chi \rangle$$

The microscope introduces a coupling between the diffracted beams when transferred by the objective lens.

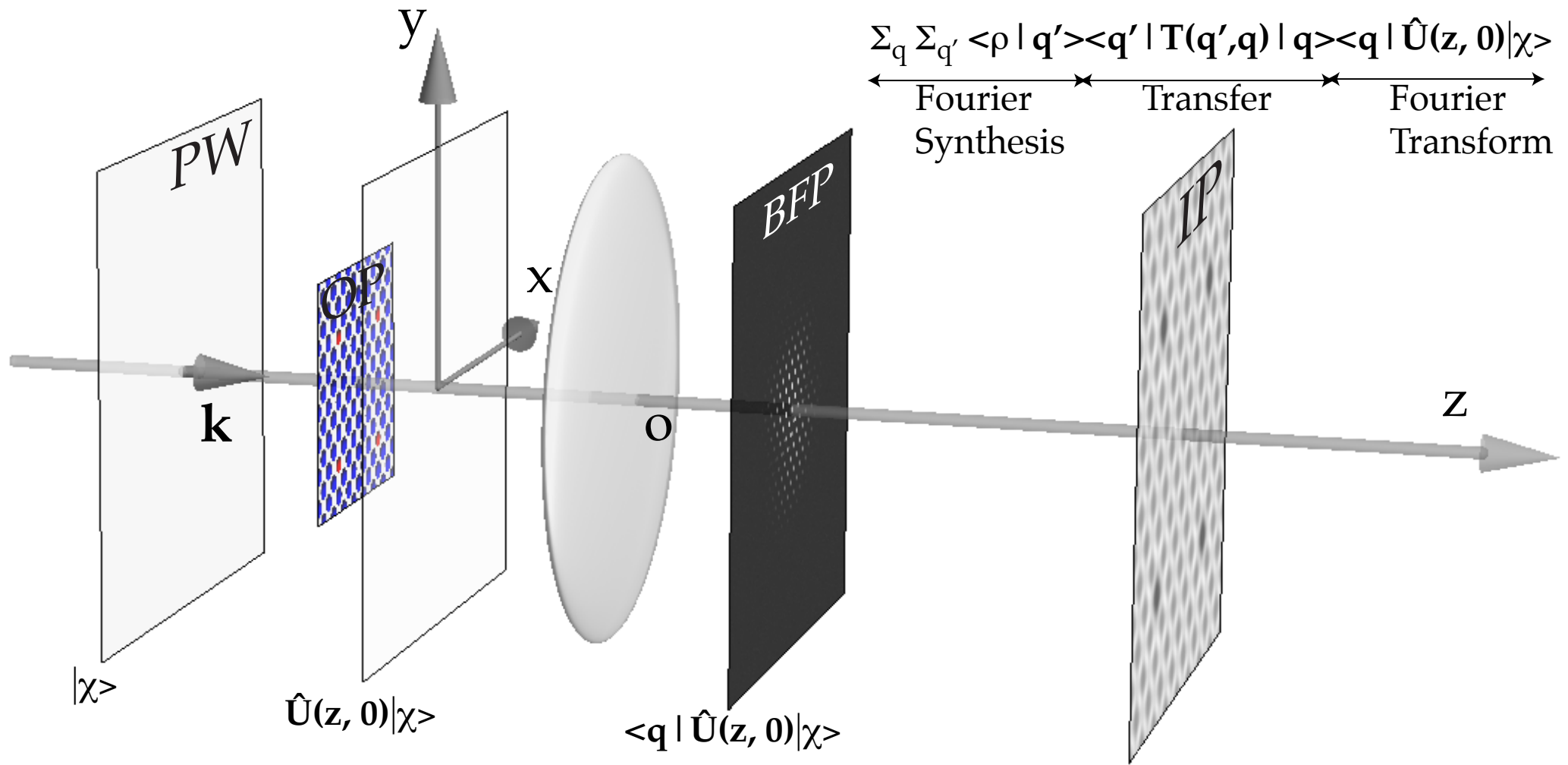
When transfer is **linear** (for example in WPOA (weak phase object approximation)) the transfer matrix $\langle q' | T(q', q) | q \rangle$ is diagonal:

$$\langle q' | T(q', q) | q \rangle = T(q) \delta(q' - q)$$

In this particularly simple case the **image intensity** is:

$$\omega_o \rightarrow \rho(z, 0) = \left| \sum_q \langle \rho | q \rangle T(q) \langle q | \hat{U}(z, 0) | \chi \rangle \right|^2$$

HRTEM modeling



Finally, let us remark that the symmetry properties of the diffraction patterns and high resolution images are intrinsically tied to the properties of the transition probabilities $\omega_o \rightarrow \rho(z, 0)$ and $\omega_\chi \rightarrow q(z, 0)$.

Evolution operator $\hat{U} \implies$ **key to understand** not only symmetries, but also contrast of bright and dark field images of defects.

This **systematic approach** due to D. Gratias and R. Portier ([1]) unifies all the different methods of image simulation in transmission electron microscopy.

Approximations

$$H(z) = \frac{1}{2K} (-\nabla^2 - \chi^2 + V(z)) = H^0 + \frac{V(z)}{2K}$$

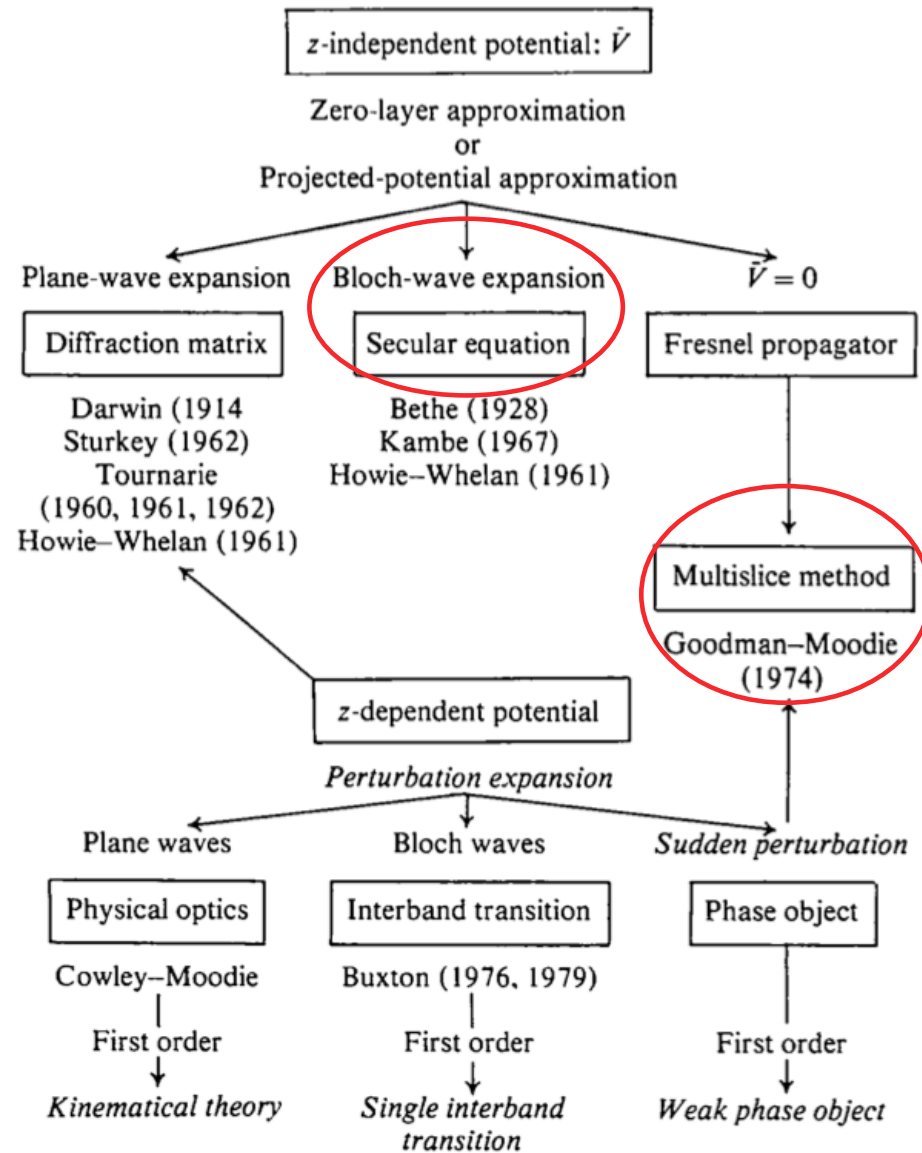


Figure: From Gratas and Portier [1]

Two approximations

All approximations are numerically equivalent, but perform best in particular cases.

We will consider only 2 approximations:

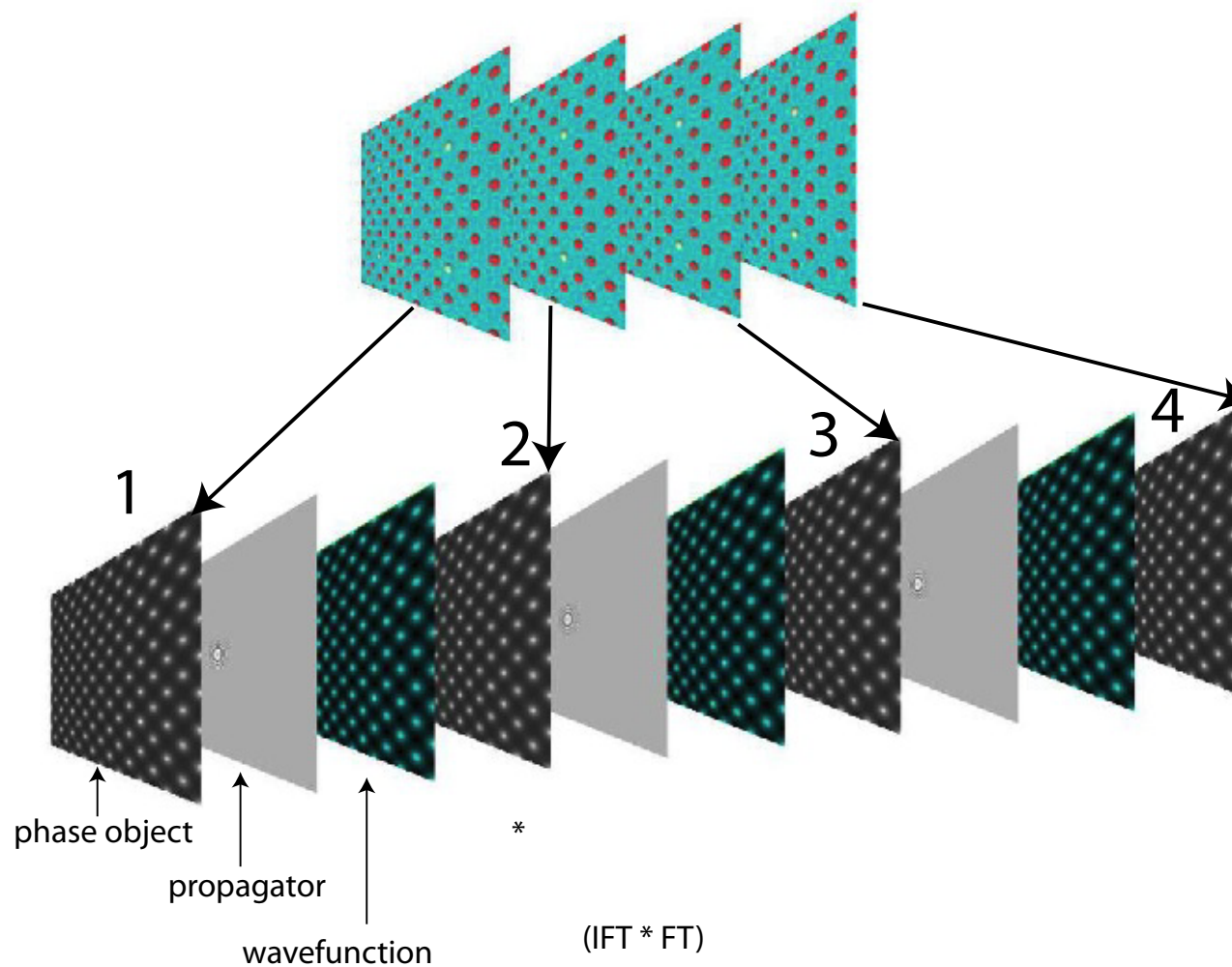
- ▶ The multislice approximation¹⁵.
- ▶ The Blochwave method¹⁶.

The multislice method performs best when simulating crystalline or amorphous solids of large unit cell or containing defects while the Bloch-wave method is adapted to the calculation of crystalline solids of small unit cell and in any $[uvw]$ orientation. The Bloch-wave method has also several advantages (speed, ease of use) for simulating CBED, LACBED or PED patterns and for polarity and chirality determination.

¹⁵J. Cowley and A.F. Moodie, Proc. Phys. Soc. B70 (1957) 486, 497 and 505.

¹⁶H. A. Bethe, Ann. Phys. 87 (1928), 55.

Multislice method



The solid is sliced into thin sub-slices. The incident wave-function is transferred by the first slice (diffraction) and propagated to the next one. The propagation is done within the Fresnel approximation, the distance between the slices being 20 - 50 times the wavelength¹⁷.

¹⁷<file:///localhost/Users/pierrestadelmann/Desktop/HamiltonJune2012/html/PtOct/b.html>

- ▶ Diffractor: transfer by a slice \Rightarrow multiplication by phase object function ($POF(\vec{\rho})$).
- ▶ Propagator: propagation between slices \Rightarrow convolution by the Fresnel propagator (is nowadays performed by FFT followed by a multiplication and an inverse FFT (FT^{-1} , multiplication, FFT)).

When only the potential term is conserved in the hamiltonian:

$$\hat{H}^d = \frac{1}{2k_z} V(\rho, z)$$

\hat{H}^d is diagonal on $|\rho\rangle$.

$$\hat{H}^d |\rho\rangle = \frac{1}{2k_z} V(\rho, z) |\rho\rangle$$

The evolution operator is then given by:

$$\hat{U}^d(z, 0) = e^{-\frac{i}{2k_z} \int_0^z V(\rho, \tau) d\tau}$$

The wave-function at thickness z is written as:

$$\Psi(z) = \hat{U}^d(z, 0) |0\rangle = e^{-\frac{i}{2k_z} \int_0^z V(\rho, \tau) d\tau} |0\rangle$$

$po(\rho) = \hat{U}^d(z, 0)$ is the phase object (PO). The weak phase object approximation (WPOA) develops PO as Taylor series. Note that in the above equation the projected potential (energy term) is negative (scattering potential times the electron charge).

Propagator

When the potential can be neglected (vacuum propagation), the hamiltonian reduces to:

$$\hat{H}^0 = -\frac{1}{2k_z} [\hat{\Delta} + \chi^2]$$

It diagonal on $|q\rangle$:

$$\hat{H}^0 |q\rangle = \frac{q^2 - \chi^2}{2k_z} |q\rangle$$

The evolution operator is then given by:

$$\hat{U}^0(z, 0) = e^{-i\hat{H}^0 z} = \int e^{-i\frac{q^2 - \chi^2}{2k_z} z} |q\rangle \langle q| d^2q$$

In $|\rho\rangle$ representation, propagation from point ρ_1 of the entrance face to point ρ_2 of the exit face of the crystal slab is:

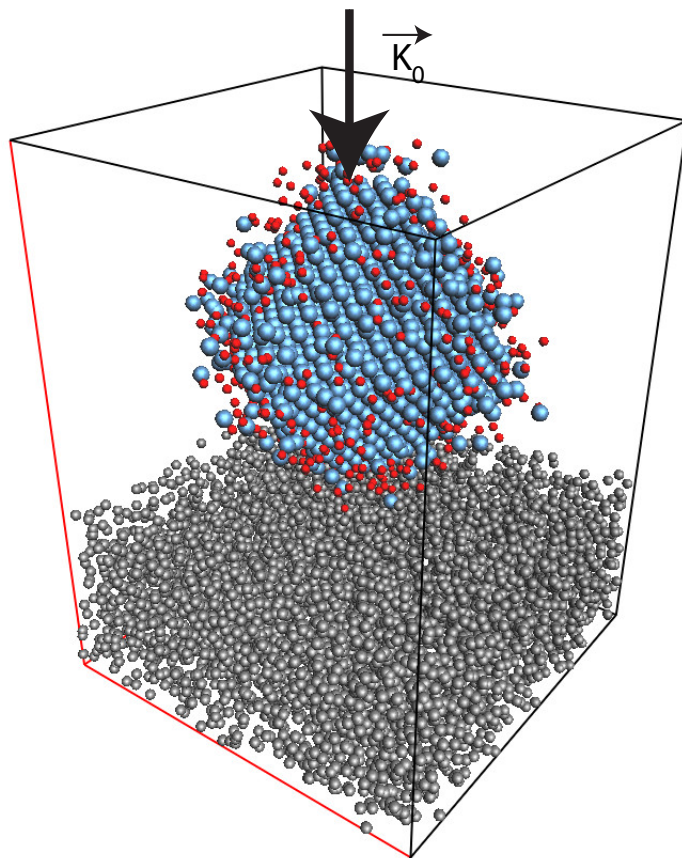
$$\langle \rho_2 | \hat{U}^0(z, 0) | \rho_1 \rangle = \int e^{-i\frac{q^2 - \chi^2}{2k_z} z} \langle \rho_2 | q \rangle \langle q | \rho_1 \rangle d^2q$$

$$\langle q | \rho_1 \rangle = e^{-iq\rho_1}$$

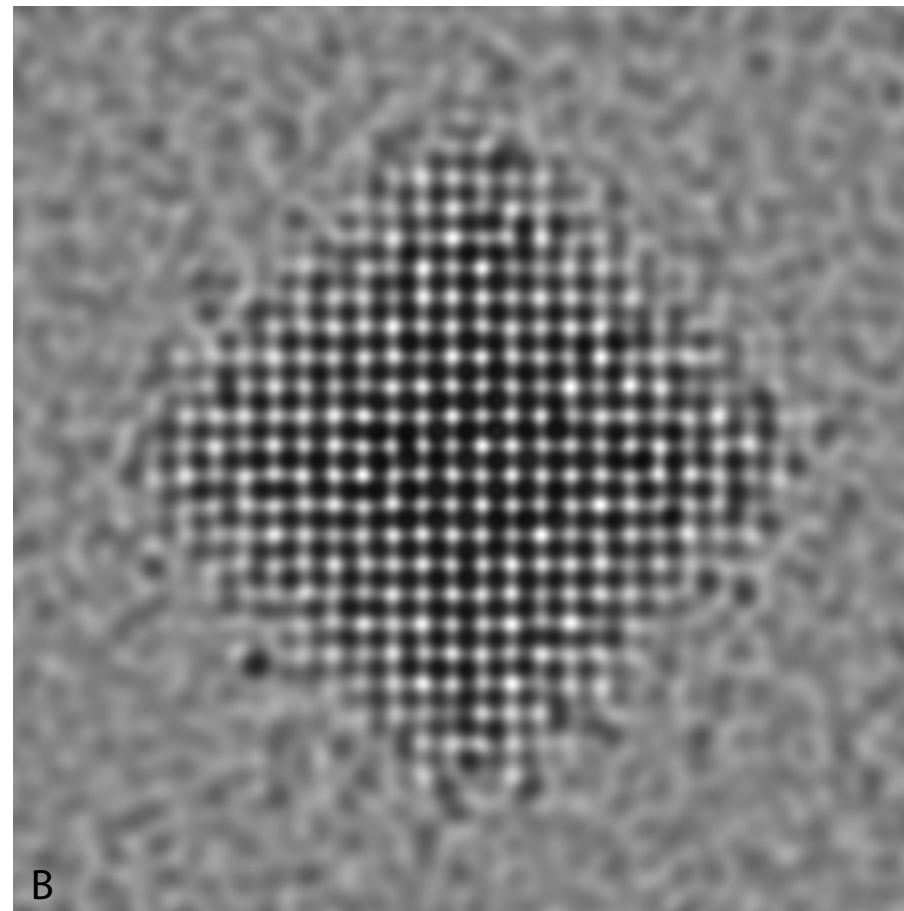
$$\langle \rho_2 | q \rangle = e^{iq\rho_2}$$

$$\hat{U}^0(z, 0) = e^{-i\frac{k_z(\rho_2 - \rho_1)^2}{2z}}$$

Example: Pt catalyst



A



B

A: catalyst model (9500 atoms)¹⁸. B: HREM image (Jeol 400kV).

Example multislice: Fe_3S_4



Figure: Fe_3S_4 HREM map.

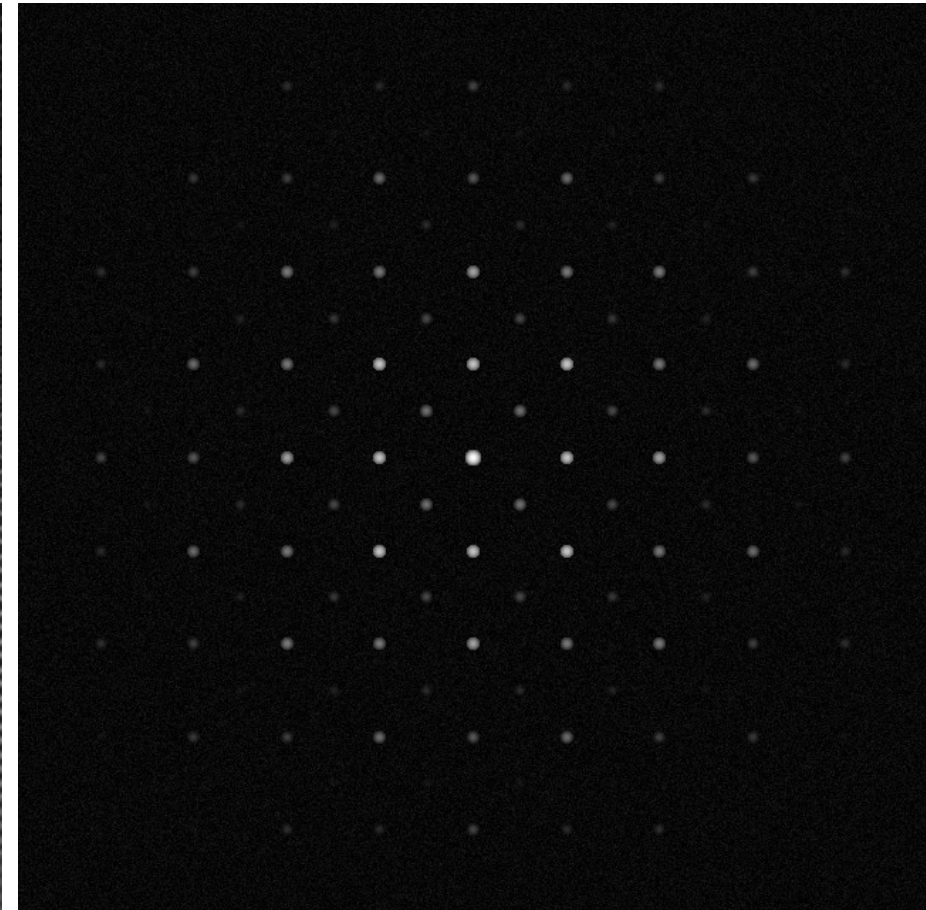


Figure: Fe_3S_4 SAED pattern.

Bloch wave method

When the scattering potential is periodic, the eigenstates $|j\rangle$ of the propagating electrons are Bloch waves. The hamiltonian of the system is projected on the eigenstates $|j\rangle$ with eigenvalues γ_j ("*anpassung*" parameter).

$$\hat{H} = \sum_j e^{-i\gamma_j} |j\rangle\langle j|$$

The evolution operator is then given by:

$$\hat{U}(z, 0) = \sum_j e^{-i\gamma_j z} |j\rangle\langle j|$$

The wave-function at z developed on plane waves basis $|q\rangle$:

$$\Psi(z) = \sum_q \phi_q(z) |q\rangle$$

$$\phi_q(z) = \langle q | \hat{U}(z, 0) | 0 \rangle = \sum_j e^{-i\gamma_j z} \langle q | j \rangle \langle j | 0 \rangle$$

$$c_0^{*j} = \langle j | 0 \rangle \quad \text{and} \quad c_q^j = \langle q | j \rangle$$

where in usual notation c_0^{*j} and c_q^j are the Bloch-wave excitations (component of the initial state $|0\rangle$ on $|j\rangle$) and coefficients (component of reflection $|q\rangle$ on $|j\rangle$) respectively.

Bloch wave coefficients c_0^{*j} and c_q^j

The Bloch wave coefficients c_0^{*j} and c_q^j are determined from:

$$\begin{aligned}\hat{H}|j\rangle &= \gamma_j|j\rangle \Rightarrow \langle q|\hat{H}|j\rangle = \gamma_j \langle q|j\rangle \\ \langle q|\frac{1}{2k_z}(-\hat{\Delta} - \chi^2 + \bar{V})|j\rangle &= \gamma_j \langle q|j\rangle \\ \frac{q^2 - \chi^2}{2k_z} \langle q|j\rangle + \sum_{q'} \langle q|\frac{\bar{V}}{2k_z}|q'\rangle \langle q'|j\rangle &= \gamma_j \langle q|j\rangle \\ \frac{q^2 - \chi^2}{2k_z} c_q^j + \frac{V_{q'-q}}{2k_z} c_{q'}^j &= \gamma_j c_q^j\end{aligned}$$

It is transformed in an homogenous system (in matrix form):

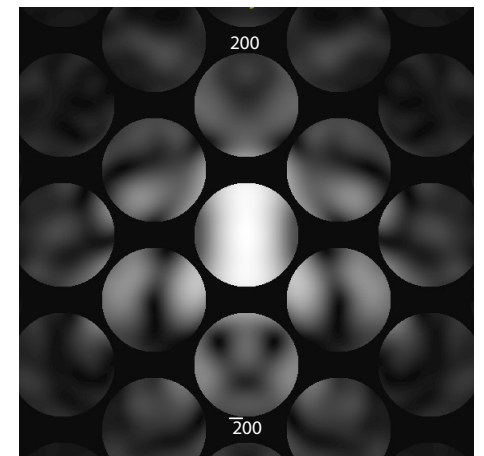
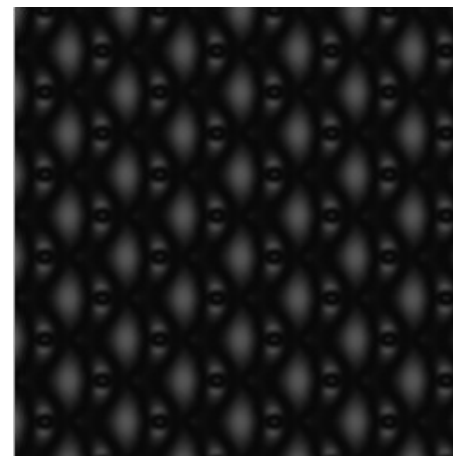
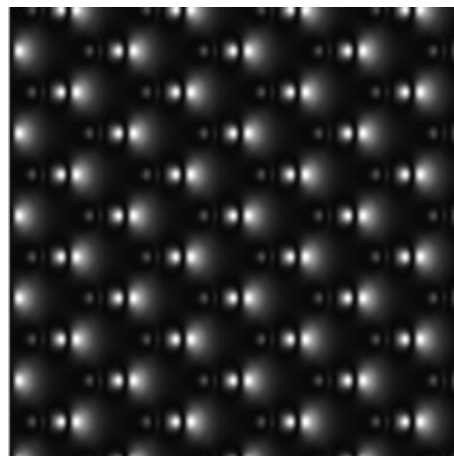
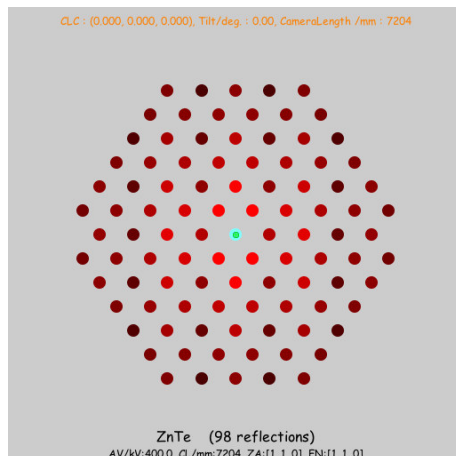
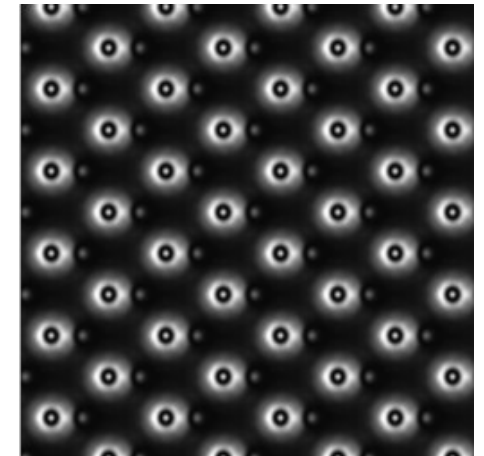
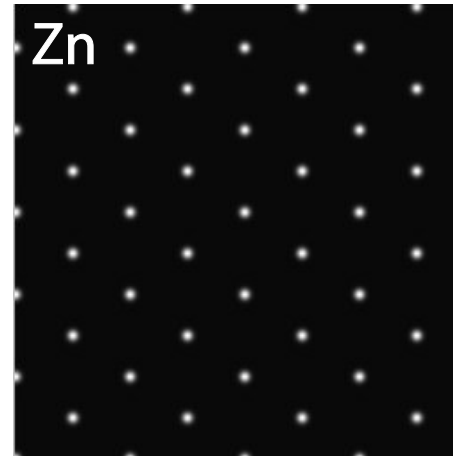
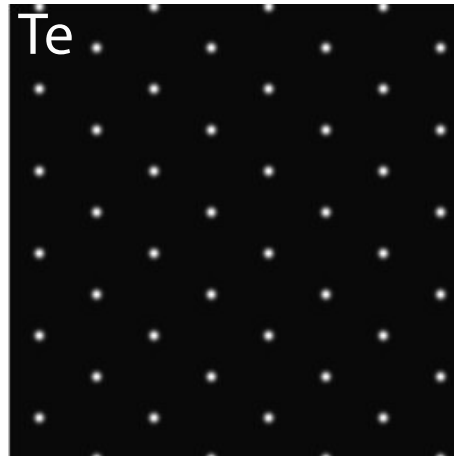
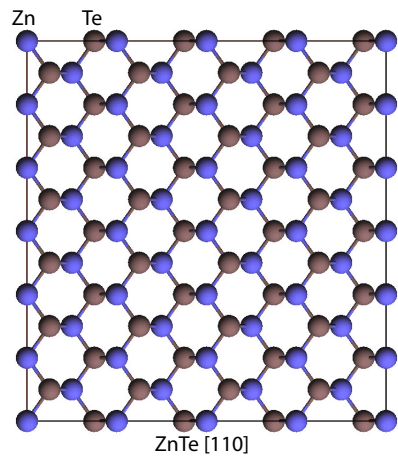
$$\left[\left[\frac{g^2 - \chi^2}{2k_z} - \lambda \hat{I} + \frac{\bar{V}_{h-g}}{2k_z} \right] \right] [c] = 0$$

The eigenvalues γ_j and eigenvectors $[c]$ are determined for a limited set of plane wave $|g_i\rangle$. In practice, the set dimension is increased until the eigenvalues converge. The Bloch waves are finally given by:

$$|j^{(n)}\rangle = \sum_i c_i^n |g_i\rangle$$

The Bloch waves (eigenstates) propagate independently in the crystal.

Example: ZnTe [110]



1 + 49 reflections. Only 5 Bloch-waves are excited when $|\chi| \geq 0$.

Bloch-wave example: LACBED - specimen thickness

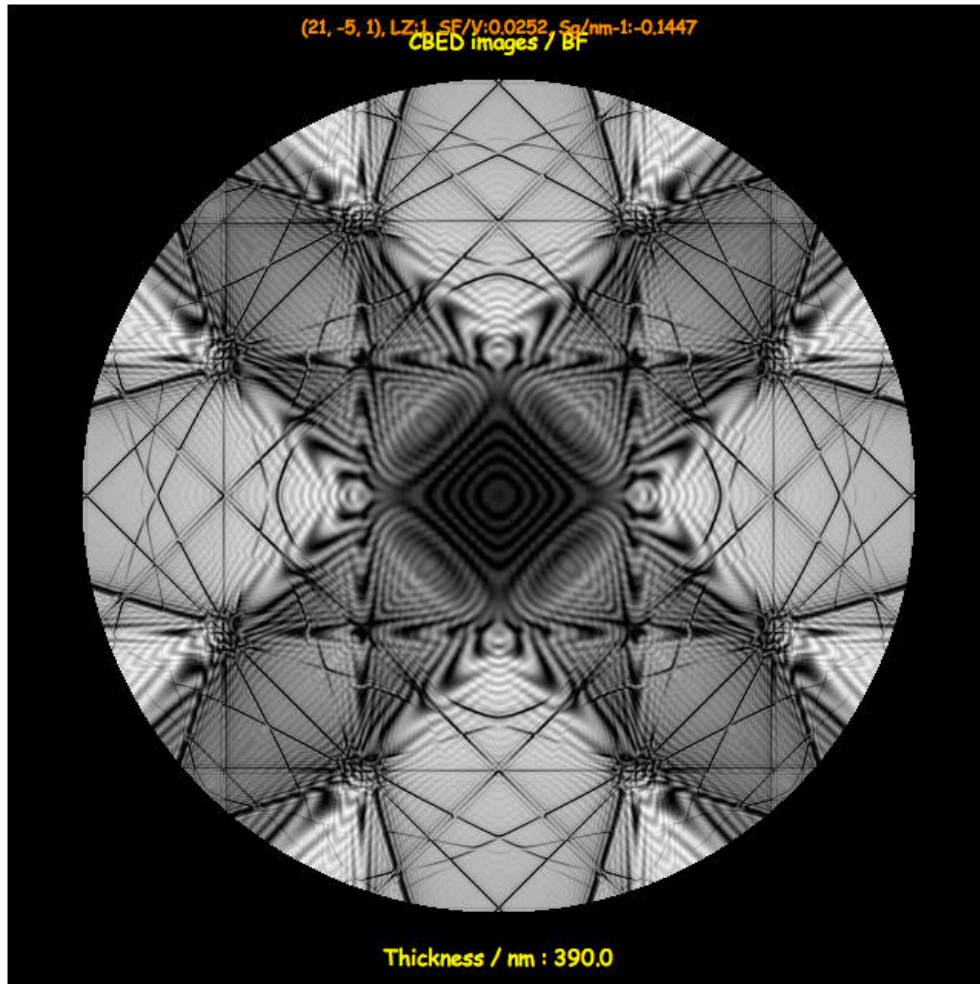


Figure: Simulation.

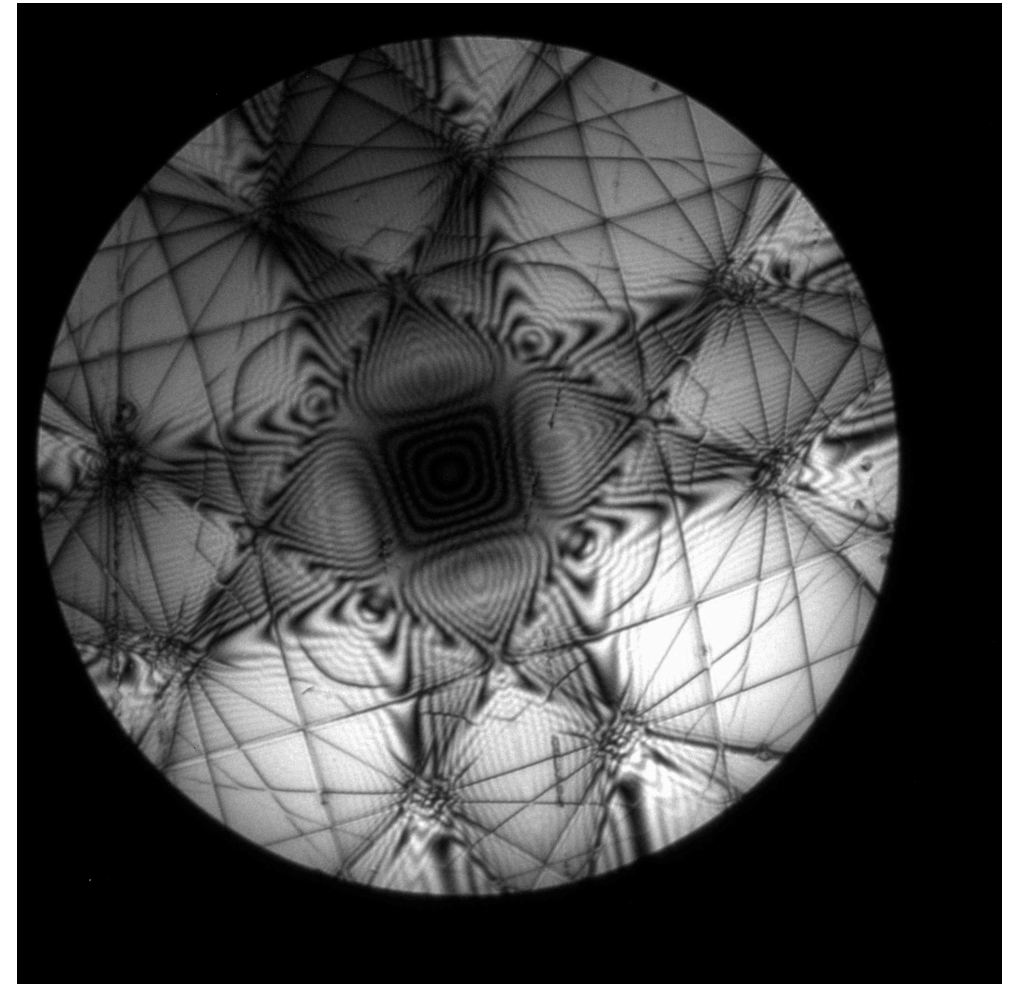
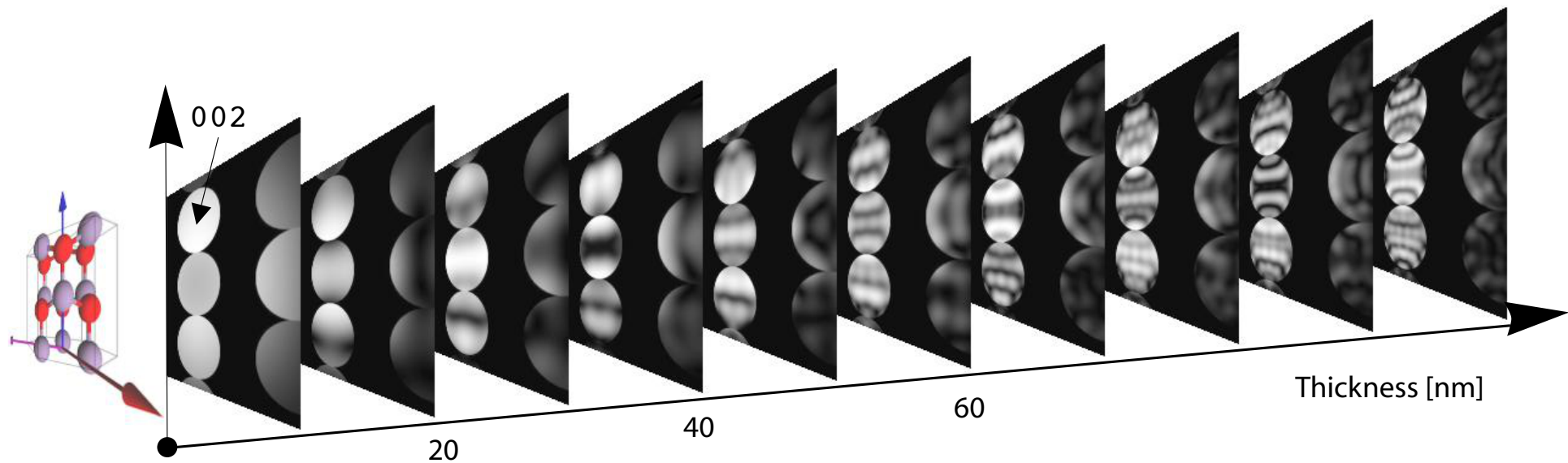


Figure: Web site EM centre - Monash university (J. Etheridge).

Bloch-wave simulation of LACBED pattern¹⁹.

¹⁹file:///localhost/Users/pierrestadelmann/Desktop/HamiltonJune2012/html/Si001/Si001.html

Bloch-wave example: ZnO polarity



(200) and ($\bar{2}00$) CBED disks show different intensity pattern ($F_{200} = 10.86 \text{ V}$, $F_{\bar{2}00} = 10.71 \text{ V}$)²⁰.

²⁰<file:///localhost/Users/pierrestadelmann/Desktop/HamiltonJune2012/Crystals/ZnO/Zn0.html>

Example: Fe_3S_4



Figure: Fe_3S_4 HREM map Bloch-wave method (1 + 436 BW)

Figure: Fe_3S_4 HREM map multislice method (256x256).

Detector MTF: Gatan 1K x 1K CCD

To make quantitative comparison with experimental HRTEM images the MTF of the detector must be introduced in the simulation.

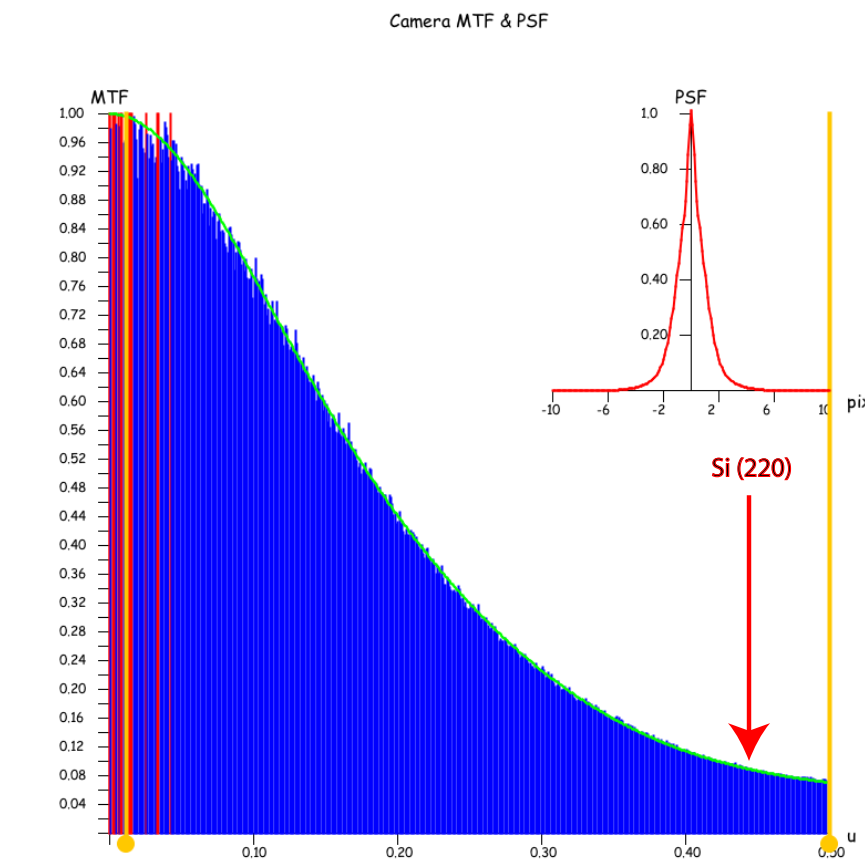
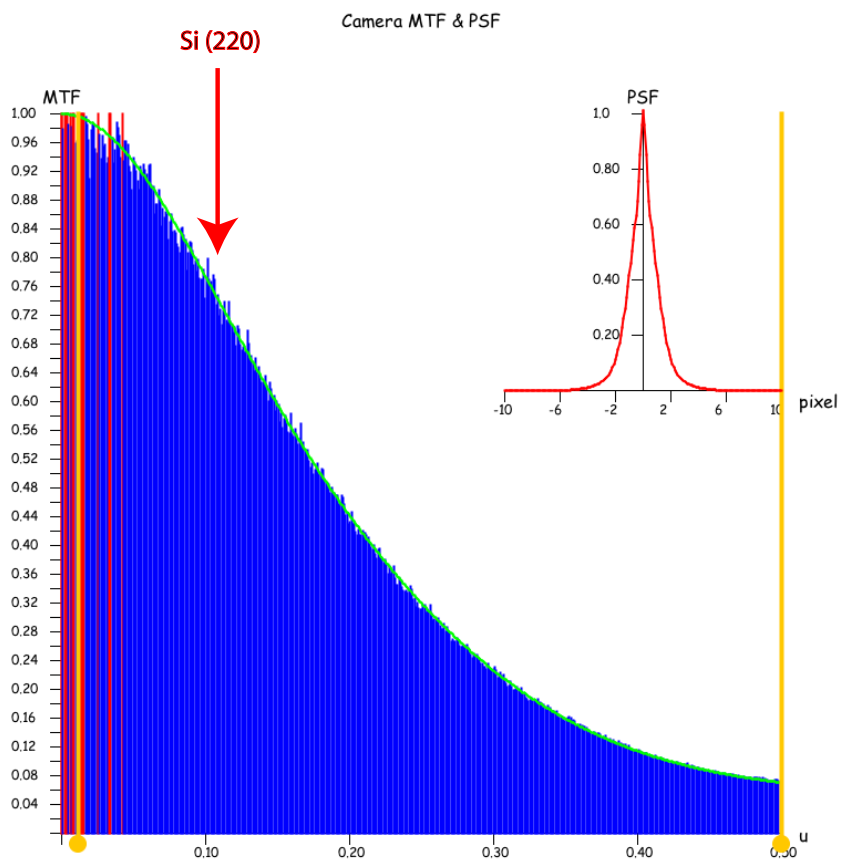


Figure: At high magnification Si (220) planes imaged with high contrast.

Figure: At low magnification Si (220) planes imaged with low contrast.

For quantitative comparison always use highest magnification!

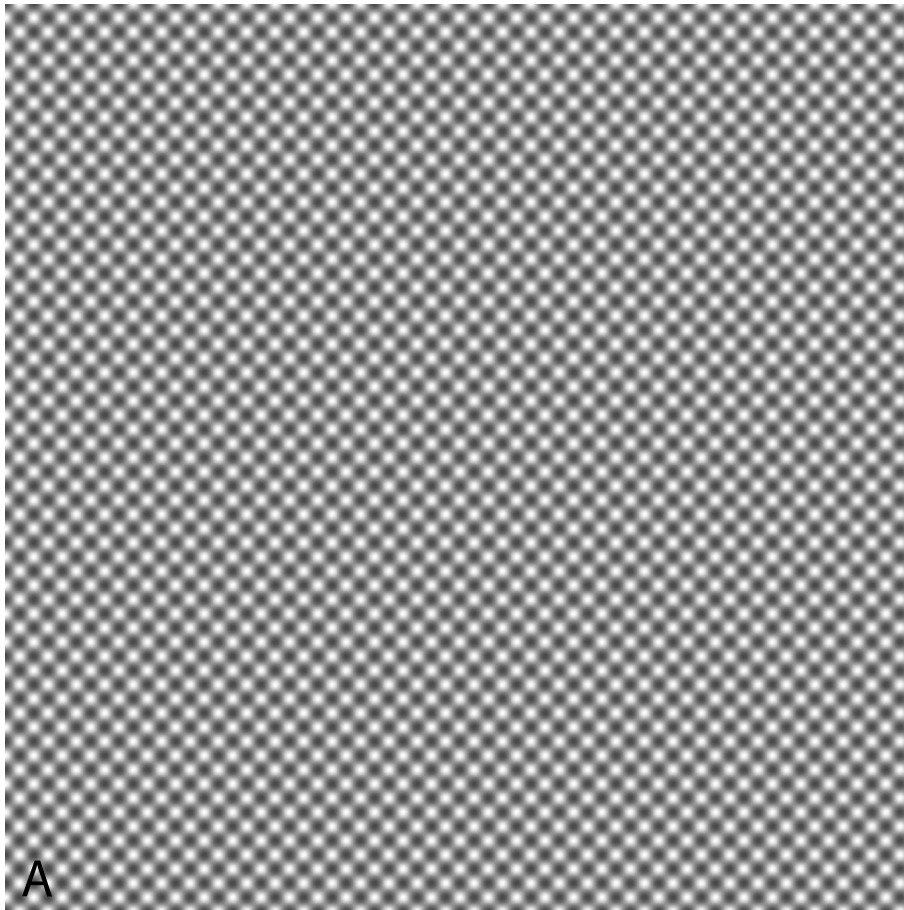


Figure: A: Si [001] simulation.

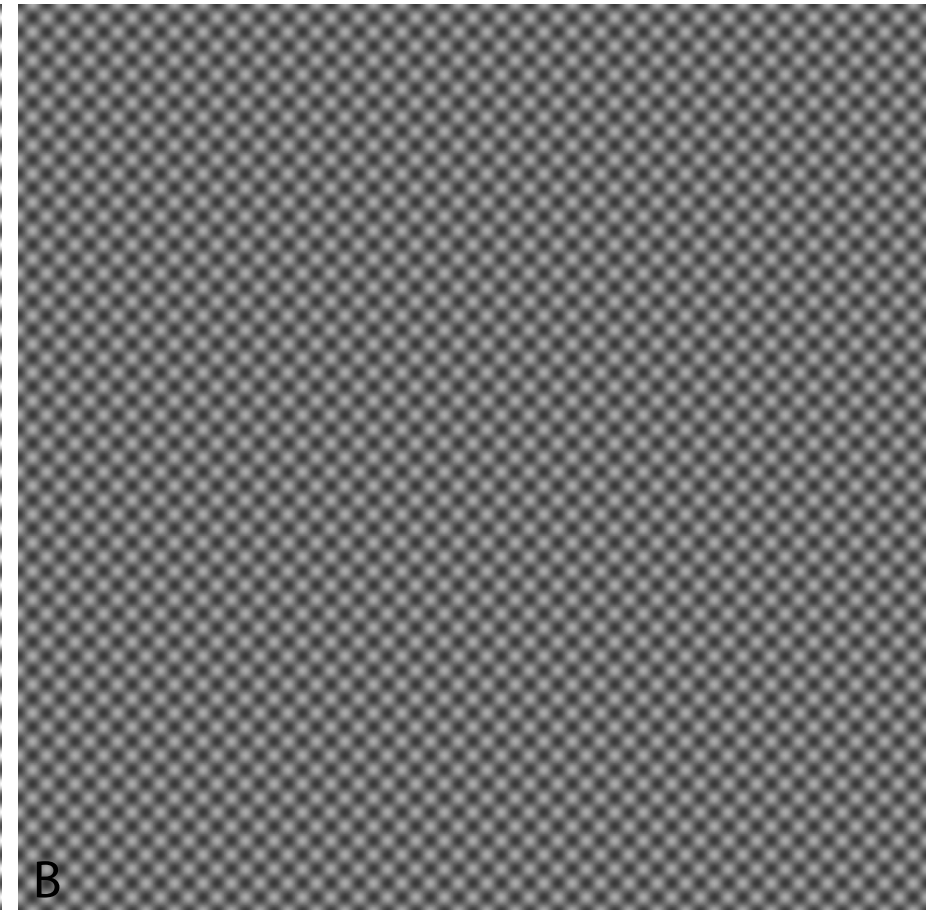


Figure: B: Si [001], simulation + CCD MTF.

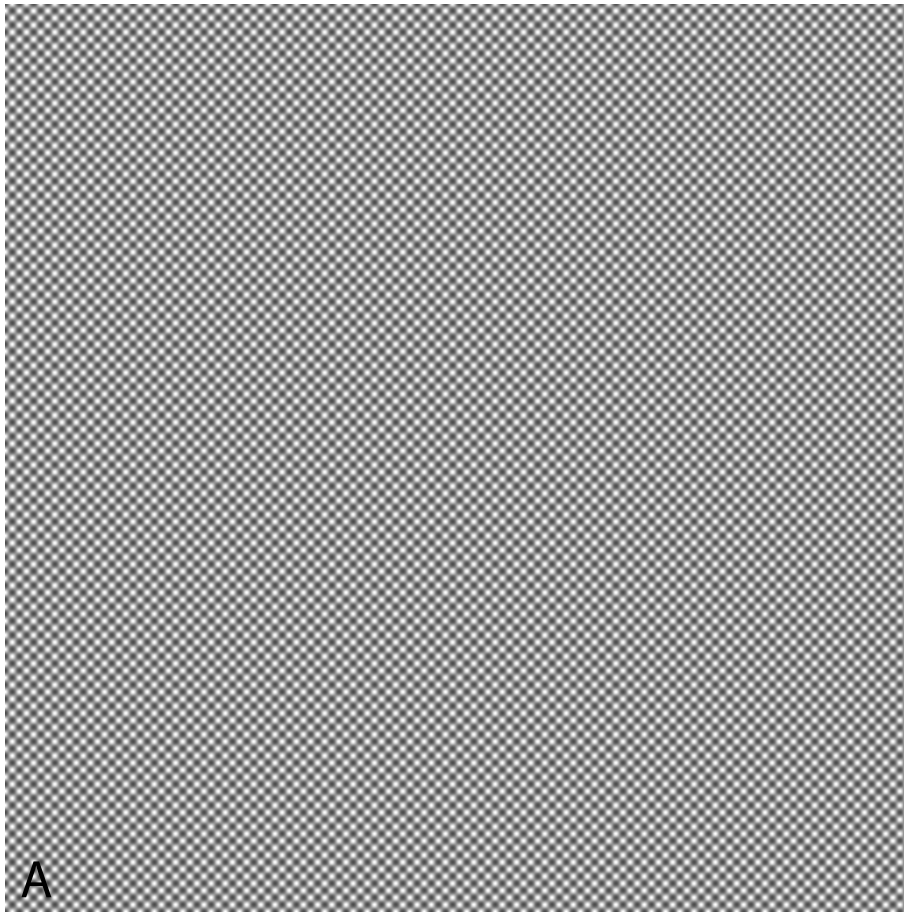


Figure: A: Si [001] simulation.

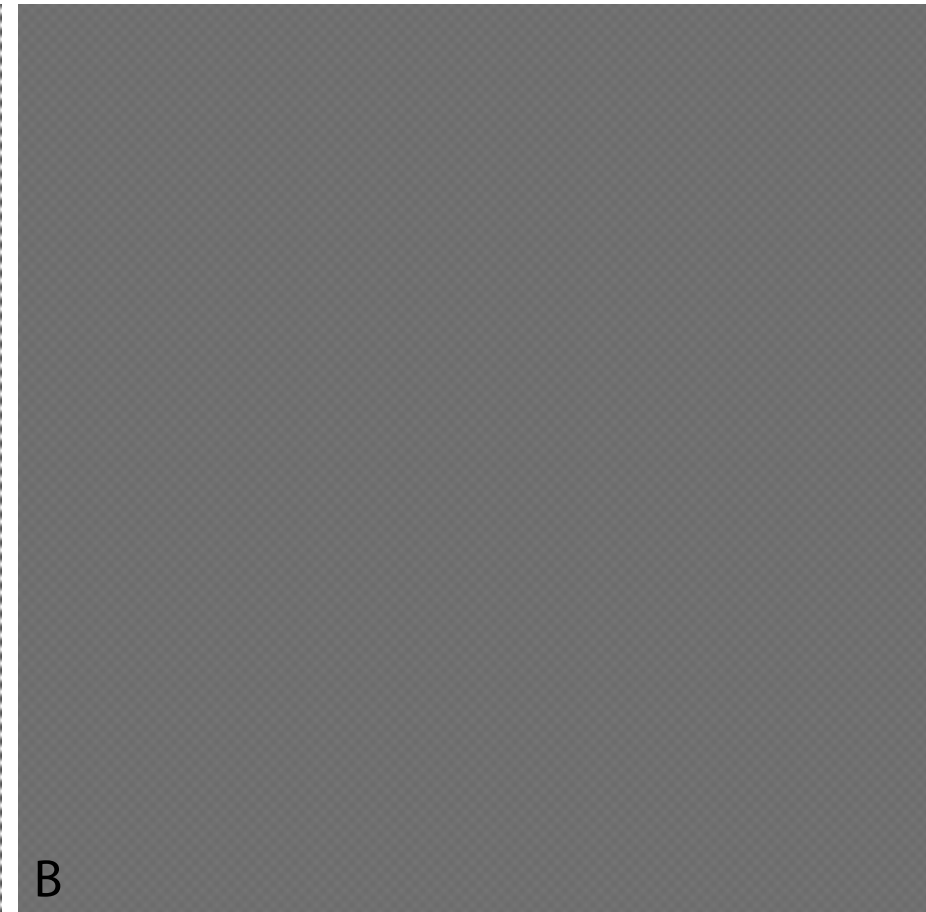
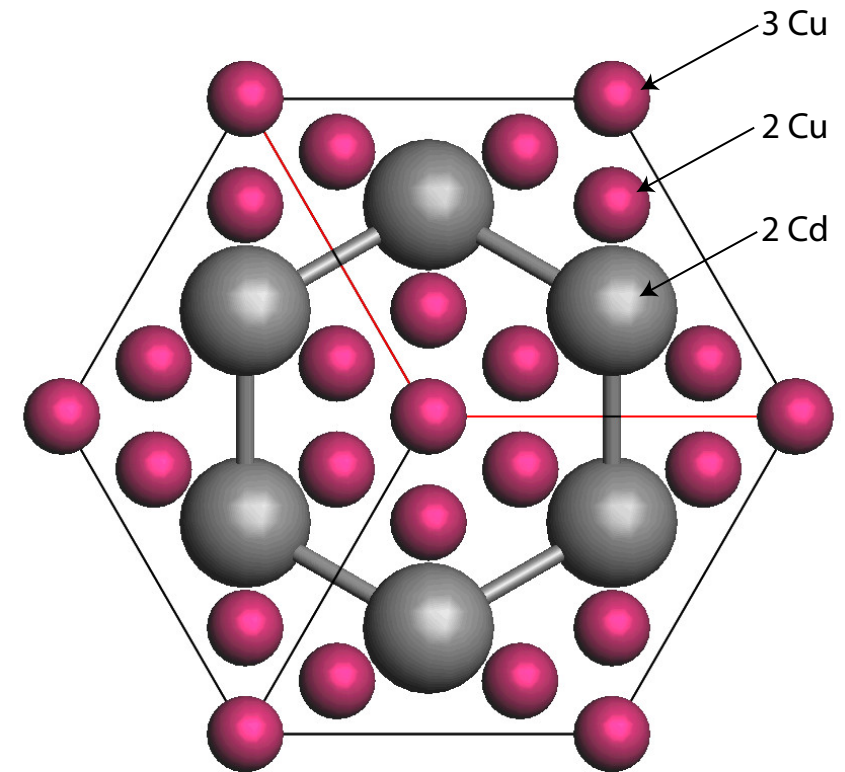
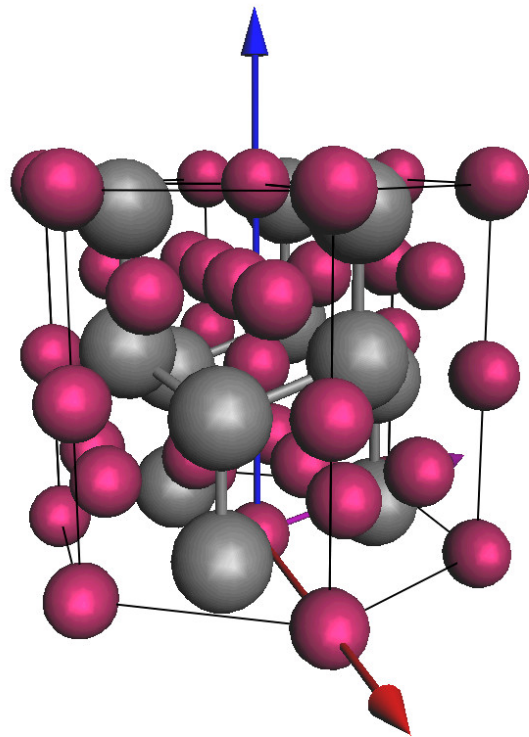


Figure: B: Si [001], simulation + CCD MTF.

Future of HRTEM simulation with the C_s and C_c correction?

Example: $CdCu_2$, visibility of the 3 Cu atomic columns.

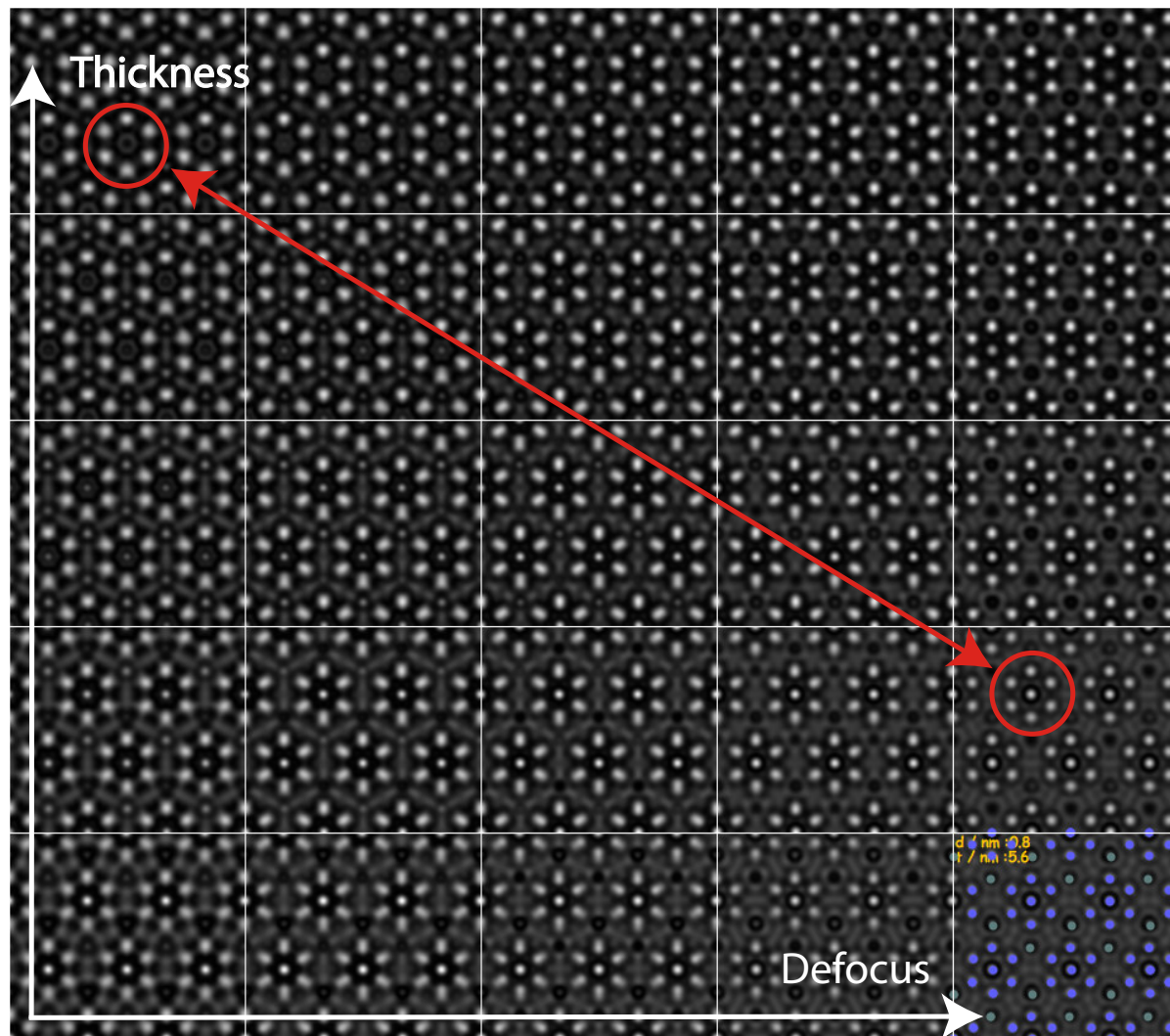


HRTEM image simulation conditions

Acc. [kV]	C_s [mm]	C_5 [mm]	C_c [mm]	ΔE [eV]	Z [nm]	Δz [nm]
300	-0.008	30	0.5	0.6	-4.9	1
300	-0.008	30	0.1	0.2	-2.0	1

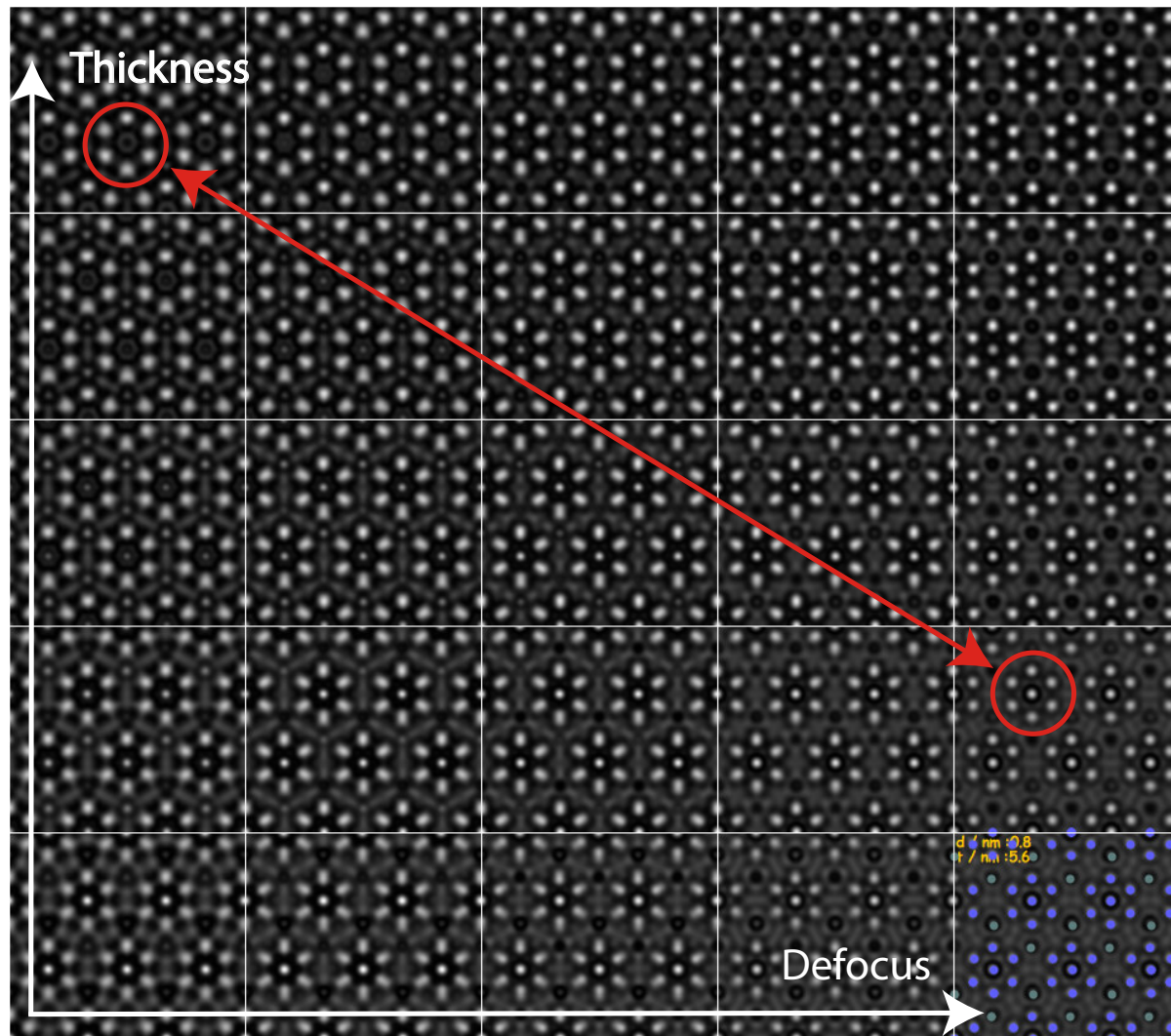
Dynamical scattering effects are not affected by C_s and/or C_c corrected TEM!

$CdCu_2[001]$: imaging parameters set 1



Visibility of 3 Cu atomic columns depends on specimen thickness and defocus.

$CdCu_2[001]$: imaging parameters set 2



Improving C_c and ΔE does not affect the visibility of 3 the Cu atomic columns depends on specimen thickness and defocus.

Visibility of the 3 Cu atomic columns is affected dynamical scattering (1 MeV C_s and C_c TEM).

Dynamical theory of elastic scattering of high energy electron

We aim to understand in details **multiple elastic scattering** of electrons by crystals.

- ▶ High energy electron (eE).
- ▶ **Periodic** interaction potential $V(\vec{r})$.
- ▶ Time **independent** flux of incident electrons.

The **fundamental equation of electron elastic scattering** by a potential V_v [Volt] (positive inside a crystal) in the approximation of a stationary flux of electrons of a given energy eE is the **Schrödinger** equation ([2]):

$$\Delta \Phi(\vec{r}) + \frac{2me}{\hbar^2} [E + V_v(\vec{r})] \Phi(\vec{r}) = 0$$

With a change of notation its is written as:

$$[\Delta + 4\pi^2 K_i^2] \Phi(\vec{r}) = -4\pi^2 V_v(\vec{r}) \Phi(\vec{r})$$

Where the wavevector $|\vec{K}_i|$ of the incident electrons is given by:

$$|K_i| = \frac{\sqrt{2meE}}{h}$$

and

$$m = \gamma m_0$$

Schrödinger equation

The Laplacian $\Delta = \frac{\partial^2}{\partial x^2} + \frac{\partial^2}{\partial y^2} + \frac{\partial^2}{\partial z^2}$ is written as: $\Delta_\rho + \frac{\partial^2}{\partial z^2}$. As a result, $[\Delta + \dots]e^{2\pi i k_z z}\Psi(\rho; z)$ is given by: $[\Delta_\rho + \frac{\partial^2}{\partial z^2} + \dots]e^{2\pi i k_z z}\Psi(\rho; z)$.

Performing the z-differentiation:

$$\frac{\partial^2}{\partial z^2}e^{2\pi i k_z z}\Psi(\rho; z) = e^{2\pi i k_z z}[-4\pi^2 k_z^2 + 4\pi i k_z \frac{\partial}{\partial z} + \frac{\partial^2}{\partial z^2}]\Psi(\rho; z)$$

Inserting the last expression and dropping the term $e^{2\pi i k_z z}$:

$$[\Delta_\rho + 4\pi^2(K_i^2 - k_z^2 + V(\rho; z)) + 4\pi i k_z \frac{\partial}{\partial z} + \frac{\partial^2}{\partial z^2}]\Psi(\rho; z) = 0$$

Since $K_i^2 = k_z^2 + \chi^2$:

$$[\Delta_\rho + 4\pi^2\chi^2 + 4\pi^2 V(\rho; z) + 4\pi i k_z \frac{\partial}{\partial z} + \frac{\partial^2}{\partial z^2}]\Psi(\rho; z) = 0$$

Rearranging the last equation:

$$i \frac{\partial \Psi(\rho; z)}{\partial z} = -\frac{1}{4\pi k_z} [\Delta_\rho + 4\pi^2\chi^2 + 4\pi^2 V(\rho; z) + \frac{\partial^2}{\partial z^2}]\Psi(\rho; z)$$

Fundamental equation

$$i \frac{\partial \Psi(\rho; z)}{\partial z} = -\frac{1}{4\pi k_z} [\Delta_\rho + 4\pi^2 \chi^2 + 4\pi^2 V(\rho; z) + \frac{\partial^2}{\partial z^2}] \Psi(\rho; z)$$

The term $|\frac{\partial^2 \Psi(\rho; z)}{\partial z^2}|$ being **much smaller** than $|k_z \frac{\partial \Psi(\rho; z)}{\partial z}|$ we drop it (this is equivalent to **neglect backscattering**).

Fundamental equation of **elastic scattering** of **high energy mono-kinetic electrons** with a potential within the approximation of **small angle scattering**:

$$i \frac{\partial}{\partial z} \Psi(\rho; z) = -\frac{1}{4\pi k_z} [\Delta_\rho + 4\pi^2 \chi^2 + 4\pi^2 V(\rho; z)] \Psi(\rho; z)$$

Time dependent Schrödinger equation \implies solution by many methods of quantum mechanics!

Remarks

- ▶ The approximations of the fundamental equation are equivalent to assume that the **scattering potential is small compared to the accelerating potential** and that k_z varies only slightly with z . It is in fact a quite good approximation, since the mean crystal potential is of the order of $10 - 20 V$.
- ▶ **Electron backscattering** is neglected, the electron are moving forwards.
- ▶ The fundamental equation is actually equivalent to a **2-dimensional Schrödinger equation** ($\rho = \{x, y\}$) where z plays the role of time. The system evolution is **causal**, from the past to the future.

Fundamental equation in **Hamiltonian** form:

$$i \frac{\partial}{\partial z} \Psi = H \psi$$

where:

$$H = -\frac{1}{4\pi k_z} [\Delta_\rho + 4\pi^2 \chi^2 + 4\pi^2 V(\rho; z)] = H_o + \frac{4\pi^2 V(\rho; z)}{4\pi k_z}$$

A **fundamental postulate of quantum mechanics** ([3, 4]) says that the evolution operator obeys the equation:

$$i \frac{\partial}{\partial z} U(z, 0) = H(\rho; z) U(z, 0)$$

Causal evolution operator

$U(z, 0)$: **unitary operator** (the norm of $|\Psi\rangle$ is conserved), in general not directly integrable \implies **approximations**.

$U(z, 0)$ can be **directly integrated** only when $H(\rho; z)$ and $\frac{\partial}{\partial z}H(\rho; z)$ commute. In that case the general solution is [3]:

$$U(z, 0) = e^{-i \int_0^z H(\tau) d\tau}$$

$H(\rho; z)$ and $\frac{\partial}{\partial z}H(\rho; z)$ commute when:

- ▶ $V(\rho; z)$ does not depend on z , i.e. $V(\rho; z) = V(\rho)$ (**perfect crystal**).
- ▶ $V(\rho; z)$ can be neglected (**free space propagation**).
- ▶ $H(\rho; z)$ is approximated by its potential term (**phase object**).

Three approximations are available in jems:

- ▶ **Multislice** method.
- ▶ **Bloch wave** method.
- ▶ **Howie-Whelan** column approximation.

The full jems version will be made available for the hands-on. Bring your laptop²¹!

²¹http://cimewww.epfl.ch/people/stadelmann/jemsv3_7624u2012.htm

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